OPA3S328 40MHz、双路、精密、低噪声、低输入偏置电流 CMOS 运算放大器，带有集成开关

1 特性

- 具有集成开关的精密运算放大器，适用于跨阻应用
- 高带宽：40MHz
- 低失调电压：60μV（最大值）
- 非常低的温漂：1μV/°C（最大值）
- 低输入偏置电流：0.2pA
- 轨至轨输入和输出
- 零交越输入级
- 低电压噪声：10 kHz 时为 6.1nV/ $\sqrt{Hz}$
- 低电流噪声：10kHz 时为 0.125pA/ $\sqrt{Hz}$
- 低泄漏开关：10pA
- 压摆率：30 V/μs
- 静态电流：每通道 3.8 mA
- 关断模式下的电流：30μA
- 关断模式下的输出阻抗：100GΩ
- 单电源电压范围：2.2V 至 5.5V
- 单位增益稳定
- 小型封装：
  - 20 导联，3.5mm x 3.5mm VQFN
  - 2.0mm x 2.0mm DSBGA

2 应用

- 光纤传输数据中心间互连
- 光学模块
- 光纤网络终端装置 (ONT)
- 小型蜂窝基站
- 数字万用表 (DMM)
- 数据采集 (DAQ)

3 说明

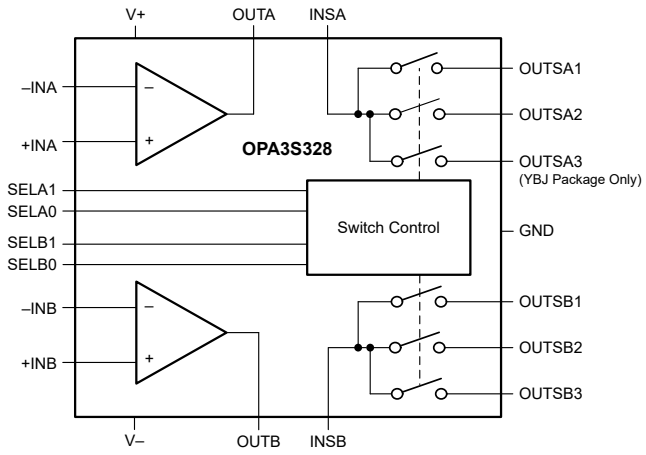
OPA3S328 是一款精密的低电压 CMOS 运算放大器 (op amp)，其集成开关针对灵活的跨阻应用进行了优化。低输入偏置电流和低输入电容允许在低光电流操作 (< 1nA) 下实现高频跨阻增益。OPA3S328 的集成开关、低偏移和轨到轨输出性能可在数十个电流值范围内实现高精度。小封装和集成开关允许可选择的跨阻增益并有助于减小空间受限应用的尺寸。

OPA3S328 采用零交叉输入技术，使输入共模范围具有灵活性，可以跨越整个电源电压范围而没有偏移偏差。该器件提供启用-禁用功能，以支持测试和测量中的便携式手持设备应用。禁用时，OPA3S328 输出阻抗通常为 100GΩ，允许使用多个跨阻通道的连线 OR 应用。

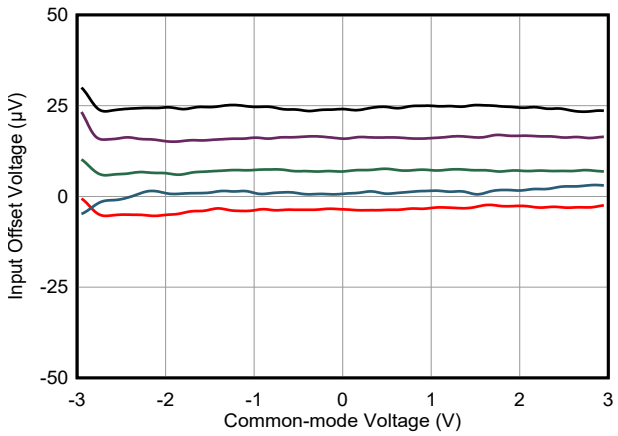
封装信息

器件型号	封装(1)	封装尺寸(2)
OPA3S328	RGR（VQFN，20）	3.5mm × 3.5mm
	YBJ（DSBGA，24）	2mm × 2mm

(1) 有关更多信息，请参阅 节 11。
(2) 封装尺寸（长 x 宽）为标称值，并包括引脚（如适用）。



功能方框图



输入失调电压与输入共模电压间的关系

本资源的原文使用英文撰写。 为方便起见，TI 提供了译文；由于翻译过程中可能使用了自动化工具，TI 不保证译文的准确性。 为确认准确性，请务必访问 ti.com 参考最新的英文版本（控制文档）。

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4 Pin Configuration and Functions

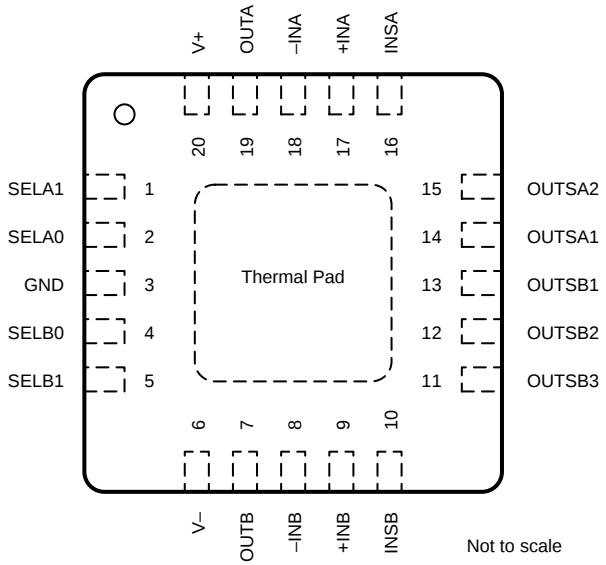

图 4-1. RGR Package, 20-Pin VQFN (Top View)

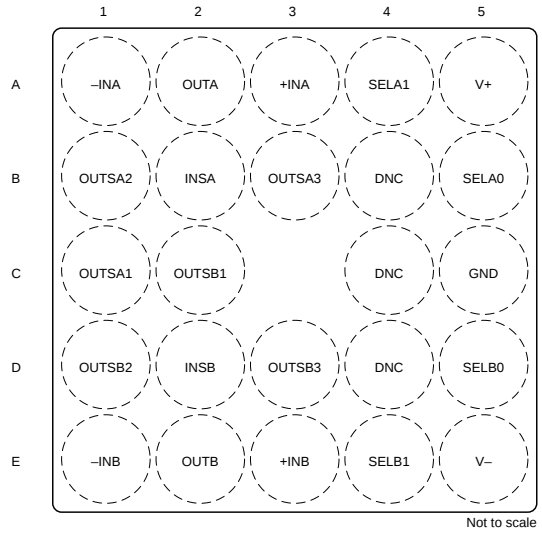

图 4-2. YBJ Package, 24-Pin DSBGA (Top View)

表 4-1. Pin Functions

PIN			TYPE	DESCRIPTION
NAME	NO.			
	RGR (VQFN)	YBJ (DSBGA)		
DNC	—	B4, C4, D4	—	Do not connect
GND	3	C5	Ground	Digital ground pin
–INA	18	A1	Input	Negative (inverting) input for amplifier A
–INB	8	E1	Input	Negative (inverting) input for amplifier B
+INA	17	A3	Input	Positive (noninverting) input for amplifier A
+INB	9	E3	Input	Positive (noninverting) input for amplifier B
INSA	16	B2	Input/Output	Switch A1, A2, A3 input
INSB	10	D2	Input/Output	Switch B1, B2, B3 input
OUTA	19	A2	Output	Output of amplifier A
OUTB	7	E2	Output	Output of amplifier B
OUTSA1	14	C1	Input/Output	Switch A1 output
OUTSA2	15	B1	Input/Output	Switch A2 output
OUTSA3	—	B3	Input/Output	Switch A3 output
OUTSB1	13	C2	Input/Output	Switch B1 output
OUTSB2	12	D1	Input/Output	Switch B2 output
OUTSB3	11	D3	Input/Output	Switch B3 output
SELA0	2	B5	Input	Input select for switch matrix A
SELA1	1	A4	Input	Input select for switch matrix A
SELB0	4	D5	Input	Input select for switch matrix B
SELB1	5	E4	Input	Input select for switch matrix B
V–	6	E5	Power	Negative (lowest) power supply
V+	20	A5	Power	Positive (highest) power supply
Thermal Pad	Thermal Pad	—	—	Exposed thermal pad. Connect to V–

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表 4-2. Select Pin Decoder

SELA1	SELA0	SELB1	SELB0	SHUTDOWN STATUS	SWITCH CONFIGURATION					
					SWITCH A1 STATUS	SWITCH A2 STATUS	SWITCH A3(1) STATUS	SWITCH B1 STATUS	SWITCH B2 STATUS	SWITCH B3 STATUS
LOW	LOW	—	—	Amplifier A enabled	CLOSED	OPEN	OPEN	—	—	—
LOW	HIGH	—	—	Amplifier A enabled	OPEN	CLOSED	OPEN	—	—	—
HIGH	LOW	—	—	Amplifier A enabled	OPEN	OPEN	CLOSED	—	—	—
HIGH	HIGH	—	—	In special mode, the SELB0 and SELB1 decoding scheme shown here is ignored, and instead, 表 4-3 applies.				—	—	—
—	—	LOW	LOW	Amplifier B enabled	—	—	—	CLOSED	OPEN	OPEN
—	—	LOW	HIGH	Amplifier B enabled	—	—	—	OPEN	CLOSED	OPEN
—	—	HIGH	LOW	Amplifier B enabled	—	—	—	OPEN	OPEN	CLOSED
—	—	HIGH	HIGH	Amplifier B enabled	—	—	—	OPEN	OPEN	OPEN

(1) Switch A3 is available in the YBJ (DSBGA-24) package option only.

表 4-3. Select Pin Decoder in Special Mode: SELA0 = SELA1 = HIGH

SELA1	SELA0	SELB1	SELB0	SHUTDOWN STATUS	SWITCH CONFIGURATION					
					SWITCH A1 STATUS	SWITCH A2 STATUS	SWITCH A3(1) STATUS	SWITCH B1 STATUS	SWITCH B2 STATUS	SWITCH B3 STATUS
HIGH	HIGH	LOW	LOW	Amplifier A in power down and amplifier B enabled	OPEN	OPEN	OPEN	OPEN	OPEN	OPEN
HIGH	HIGH	LOW	HIGH	Amplifier A enabled and amplifier B in power down	OPEN	OPEN	OPEN	OPEN	OPEN	OPEN
HIGH	HIGH	HIGH	LOW	Both Amplifier A and amplifier B enabled	OPEN	OPEN	OPEN	OPEN	OPEN	OPEN
HIGH	HIGH	HIGH	HIGH	Both Amplifier A and amplifier B in power down	OPEN	OPEN	OPEN	OPEN	OPEN	OPEN

(1) Switch A3 is available in the YBJ (DSBGA-24) package option only.

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5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
V_S	Supply voltage, V_S = (V+) – (V–)	–0.3	6	V
	Input voltage, all pins	(V–) – 0.3	(V+) + 0.3	V
	Input current (INA+, INA–, INB+, INB–, INSA/B, OUTSA/B/1/2/3)	–10	+10	mA
	Output short-circuit(2)	Continuous	Continuous	
T_A	Operating temperature	–55	150	°C
T_{stg}	Storage temperature	–65	150	°C

(1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
(2) Short-circuit to ground, one amplifier per package.

5.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001(1)	±2000	V
		Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002(2)	±500	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
V_S	Supply voltage	Single-supply	2.2		5.5	V
		Dual-supply	±1.1		±2.75	V
V_D	Digital supply voltage, V_D = (V+) – (GND)		1.8		5.5	V
T_A	Specified temperature		–40		+125	°C

5.4 Thermal Information

THERMAL METRIC(1)		OPA3S328		UNIT
		RGR (VQFN)	YBJ (DSBGA)	
		20 PINS	24 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	43.7	66.4	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	41.7	0.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	19.5	15.6	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	0.8	0.1	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	19.5	15.6	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	5.3	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

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5.5 Electrical Characteristics

at T_A = 25°C, V_S = ±1.1 V to ±2.75 V (2.2 V to 5.5 V), R_L = 10 kΩ connected to V_S / 2, V_{CM} = V_S / 2, V_{OUT} = V_S / 2, and all voltages referred to V – (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
OFFSET VOLTAGE							
V_{OS}	Input offset voltage				10	±60	µV
		T_A = 0°C to 85°C				±90	
		T_A = –40°C to +125°C				±175	
dV_{OS}/dT	Input offset voltage drift	T_A = –40°C to +125°C			±0.15	±1	µV/°C
PSRR	Power supply rejection ratio	V_S = ±1.1 V to ±2.75 V			±1	±10	µV/V
			T_A = –40°C to +125°C		±15		
	Channel separation	f = dc			140		dB
		f = 100 kHz			75		
INPUT BIAS CURRENT							
I_B	Amplifier input bias current				±0.2	±10	pA
		T_A = 0°C to 85°C				±10	
		T_A = –40°C to +125°C				±100	
I_{OS}	Amplifier input offset current				±0.2	±20	pA
		T_A = 0°C to 85°C				±20	
		T_A = –40°C to +125°C				±200	
NOISE							
	Input voltage noise	f = 0.1 Hz to 10 Hz			3		μV_{PP}
e_N	Input voltage noise density	f = 100 Hz			25		nV/√Hz
		f = 1 kHz			9.8		
		f = 10 kHz			6.1		
i_N	Input current noise	f = 10 kHz			0.04		pA/√Hz
INPUT VOLTAGE							
V_{CM}	Common-mode voltage			(V–) – 0.1		(V+) + 0.1	V
CMRR	Common-mode rejection ratio	(V–) – 0.1 V < V_{CM} < (V+) + 0.1 V		106	120		dB
			T_A = –40°C to +125°C	96	110		
INPUT CAPACITANCE							
Z_{ID}	Differential				1 || 4		TΩ || pF
Z_{ICM}	Common-mode				1 || 2		TΩ || pF
OPEN-LOOP GAIN							
A_{OL}	Open-loop voltage gain	(V–) + 100 mV < V_O < (V+) – 100 mV		108	132		dB
			T_A = –40°C to +125°C	96	130		
		(V–) + 100 mV < V_O < (V+) – 100 mV, R_L = 2 kΩ		106	123		
			T_A = –40°C to +125°C	90	120		

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5.5 Electrical Characteristics（续）

at T_A = 25°C, V_S = ±1.1 V to ±2.75 V (2.2 V to 5.5 V), R_L = 10 kΩ connected to V_S / 2, V_{CM} = V_S / 2, V_{OUT} = V_S / 2, and all voltages referred to V– (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
FREQUENCY RESPONSE							
GBW	Gain-bandwidth product				40		MHz
SR	Slew rate	4-V step, G = +1			±30		V/μs
t_S	Settling time	To 0.1%, 4-V step , G = +1			0.3		μs
		To 0.01%, 4-V step , G = +1			0.42		
	Overload recovery time	V_{IN} × G > V_S			0.5		μs
THD+N	Total harmonic distortion + noise	V_O = 1 V_{RMS}, G = +1, f = 1 kHz			0.00017%		
f_{CP}	Charge pump frequency				27		MHz
OUTPUT							
	Voltage output swing from both rails	V_S = 2.2 V				5	mV
			R_L = 2 kΩ			15	
		V_S = 5.5 V				5	
			R_L = 2 kΩ			15	
I_{SC}	Short-circuit current	Sinking, V_S = 5.5 V			–68		mA
		Sourcing, V_S = 5.5 V			63		
Z_O	Open-loop output impedance	f = 10 kHz			55		Ω
OUTPUT DISABLE							
I_{QPD}	Quiescent current in power down	Total quiescent current, both amplifiers A and B disabled			30	50	μA
t_{PDOFF}	Output enable time				10		μs
t_{PD}	Output disable time				3		μs
Z_{PD}	Output impedance in power down				100 || 16		GΩ || pF
POWER SUPPLY							
I_Q	Quiescent current per amplifier	I_O = 0 mA			3.8	4.5	mA
			T_A = –40°C to +125°C			5.0	
SELECT INPUTS							
V_{IH}	High level input voltage	GND = 0 V		1.5		V+	V
V_{IL}	Low level input voltage	GND = 0 V		0		0.3	V
	GND voltage input range			(V–)		(V+) – 1.8	V
R_{PD}	Input pulldown resistance	SELA/B/0/1 pins			10		MΩ

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5.5 Electrical Characteristics（续）

at T_A = 25°C, V_S = ±1.1 V to ±2.75 V (2.2 V to 5.5 V), R_L = 10 kΩ connected to V_S / 2, V_{CM} = V_S / 2, V_{OUT} = V_S / 2, and all voltages referred to V – (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
SWITCHES							
t_{ON}	Switching time off to on (open to close)	R_{L_SW} = 300 Ω, C_L = 35 pF, INSA/B = 5 V, OUTSA/B/1/2/3 = 0 V, V_S = 5 V			1.3		µs
t_{OFF}	Switching time on to off (close to open)	R_{L_SW} = 300 Ω, C_L = 35 pF, INSA/B = 5 V, OUTSA/B/1/2/3 = 0 V, V_S = 5 V			2		µs
I_{L_INS}	Switch input leakage current (INSA/B)	Switch open, INSA/B = 5 V, OUTSA/B/1/2/3 = 0 V			30		pA
		Switch open, INSA/B = 1.5 V, OUTSA/B/1/2/3 = 4.5 V			10	150	
			T_A = 0°C to 85°C		25	150	
			T_A = –40°C to +125°C		82	260	
I_{L_OUTS}	Switch output leakage current (OUTSA/B/1/2/3)	Switch open, INSA/B = 1.5 V, OUTSA/B/1/2/3 = 4.5 V			11	90	pA
			T_A = 0°C to 85°C		100	120	
			T_A = –40°C to +125°C		190	250	
I_{L_ON}	Channel on leakage	Switch closed, INSA/B = 5 V, OUTSA/B/1/2/3 = 5 V			5	20	pA
			T_A = 0°C to 85°C			140	
			T_A = –40°C to +125°C			155	
C_{IN}	Switch input capacitance	Switch open, INSA/B = 2.5 V			3		pF
C_{OUT}	Switch output capacitance	Switch open, OUTSA/B/1/2/3 = 2.5 V			0.7		pF
	Switch total capacitance	Switch closed, INSA/B = OUTSA/B/1/2/3 = 2.5 V			6		pF
R_{ON}	Switch on resistance	Switch closed, V+ = 5 V, INSA/B = 2.5 V			84	125	Ω
			T_A = 0°C to 85°C		88		
			T_A = –40°C to +125°C		102		
ΔR_{ON}	Switch on resistance match between channels	Switch closed, V+ = 5 V, INSA/B = 4 V			0.2	2	Ω
	Switch on resistance flatness (vs input signal range)	Switch closed, V+ = 5 V, INSA/B = 0 V to V+			27	40	Ω
			T_A = –40°C to +125°C			100	
	Switch charge injection	C_{L_SW} = 1 nF			6		pC
	Switch off isolation	R_{L_SW} = 50 Ω, C_{L_SW} = 5 pF, f = 1 MHz			84		dB
	Switch channel-to-channel crosstalk	R_{L_SW} = 50 Ω, C_{L_SW} = 5 pF, f = 1 MHz			76		dB
	Switch −3-dB bandwidth	R_{L_SW} = 50 Ω, C_{L_SW} = 5 pF			350		MHz

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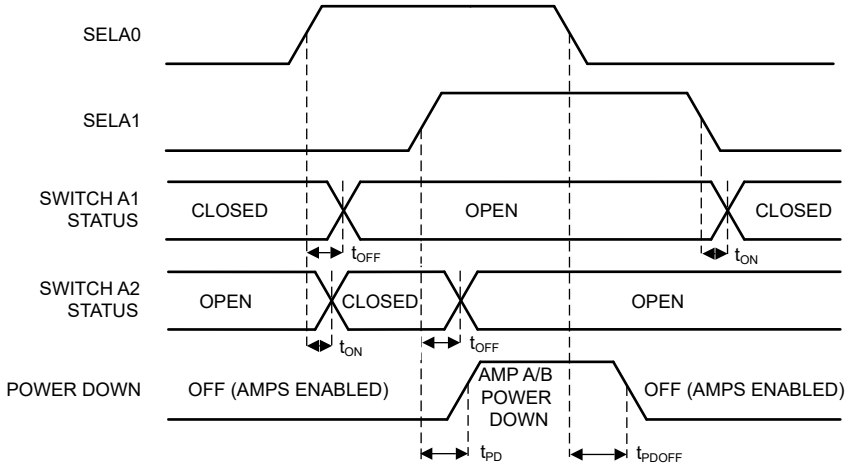
5.6 Timing Diagram



Note: SELA0 and SELA1 shown. Timing for SELB0 and SELB1 to SWITCH B1, B2 and B3 transitions matches SELA0 and SELA1.

图 5-1. Select Pin Timing Diagram

5.7 Typical Characteristics

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)

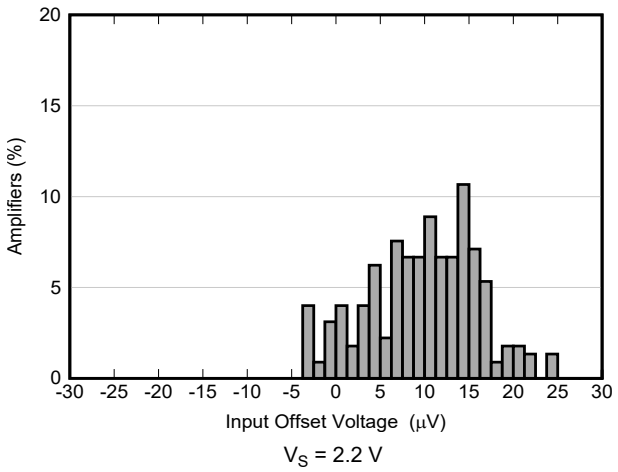


图 5-2. Offset Voltage Production Distribution

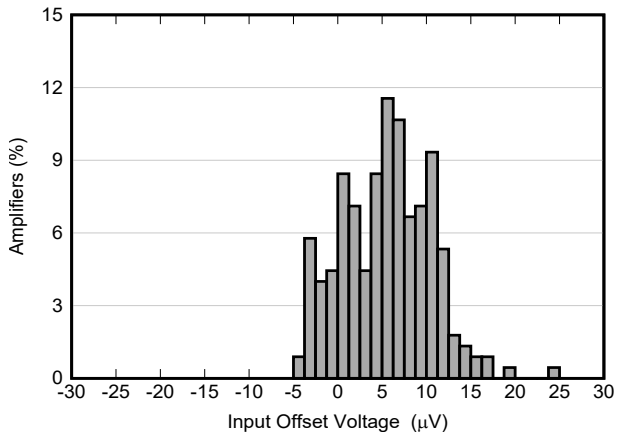


图 5-3. Offset Voltage Production Distribution

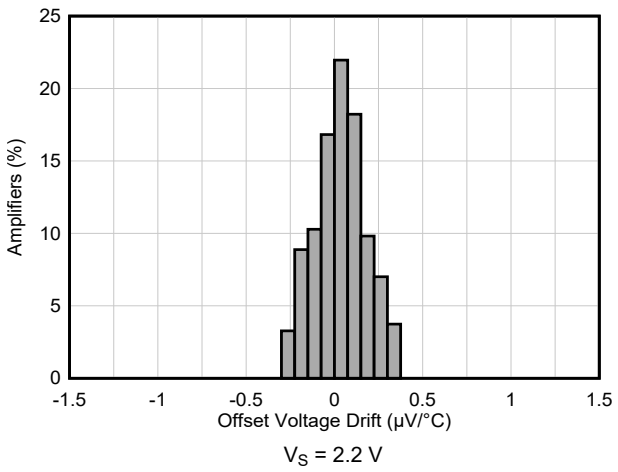


图 5-4. Offset Voltage Drift Distribution

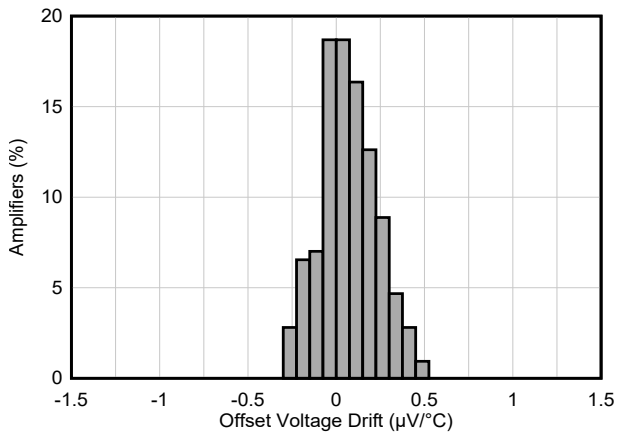


图 5-5. Offset Voltage Drift Distribution

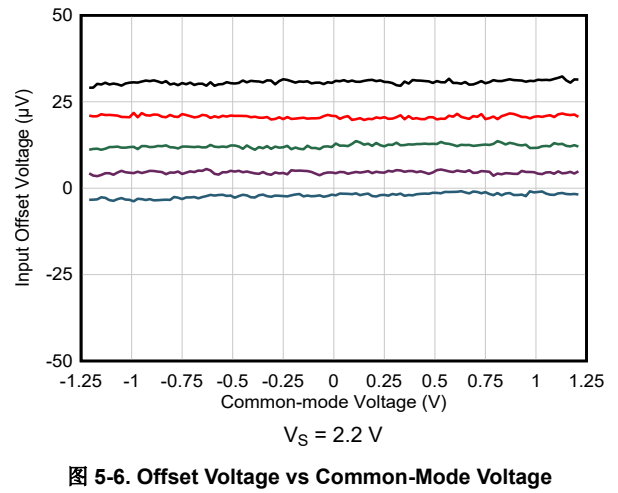


图 5-6. Offset Voltage vs Common-Mode Voltage

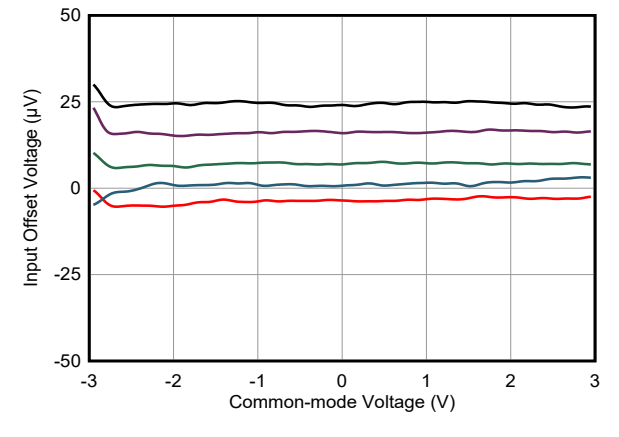


图 5-7. Offset Voltage vs Common-Mode Voltage

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5.7 Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)

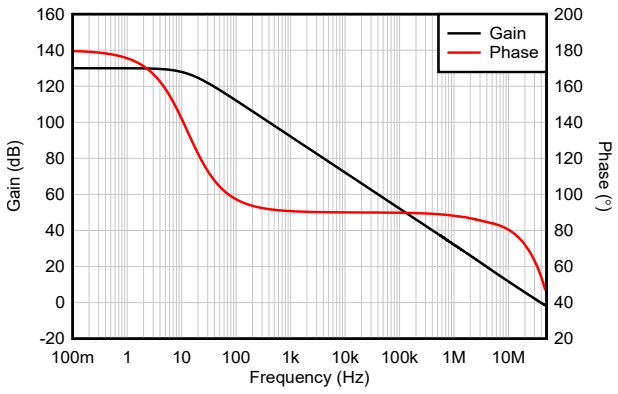

图 5-8. Open-Loop Gain/Phase vs Frequency

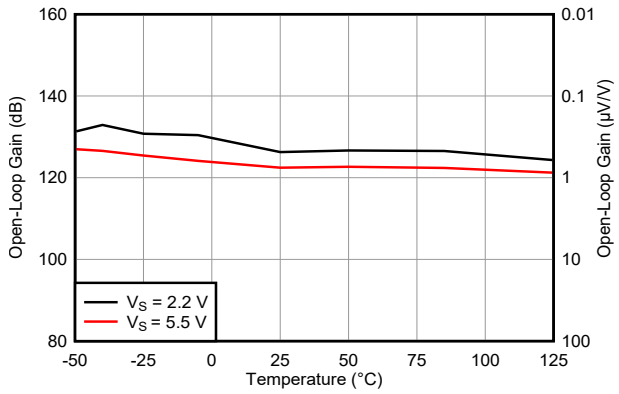

图 5-9. Open-Loop Gain vs Temperature

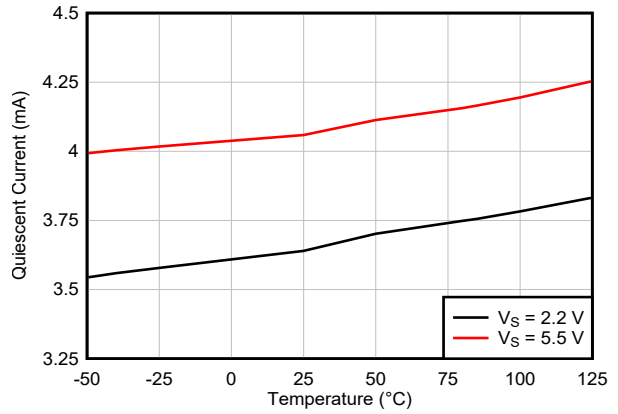

图 5-10. Quiescent Current vs Supply Voltage

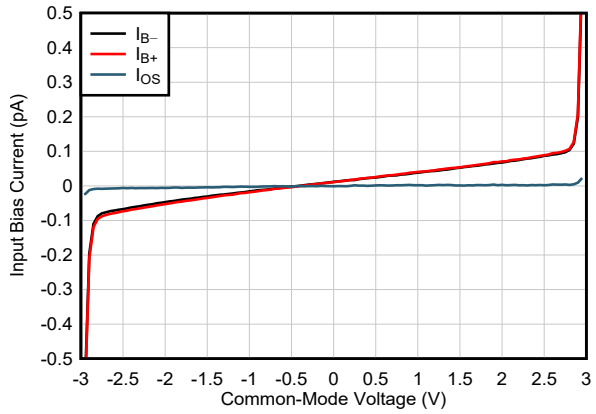

图 5-11. Input Bias Current vs Common-Mode Voltage

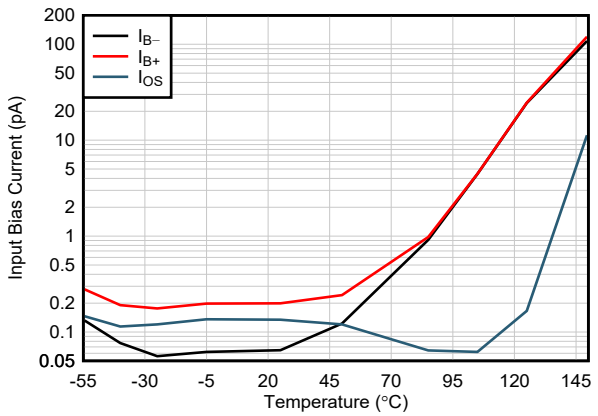

图 5-12. Input Bias Current vs Temperature

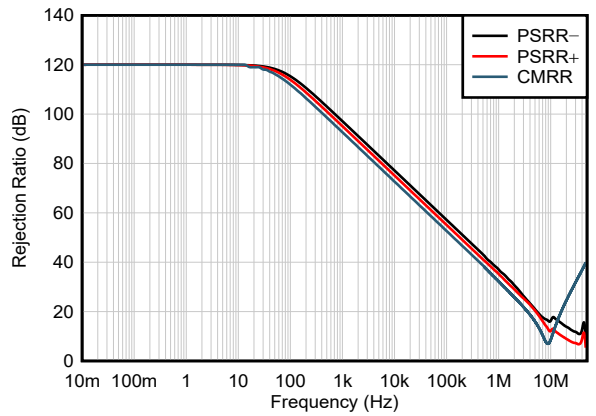

图 5-13. CMRR and PSRR vs Frequency

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5.7 Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)

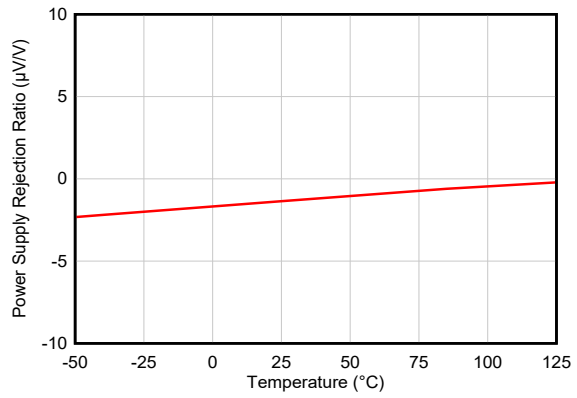

图 5-14. PSRR vs Temperature

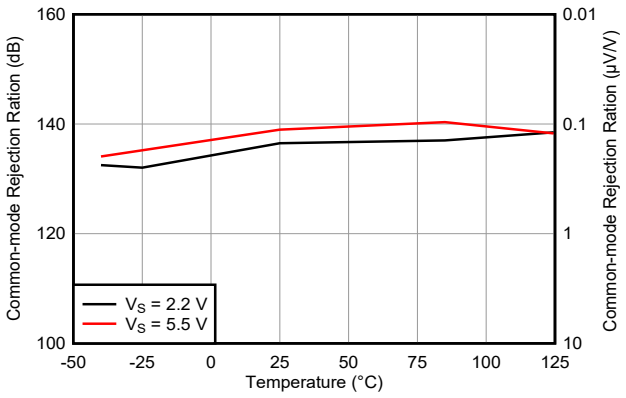

图 5-15. CMRR vs Temperature

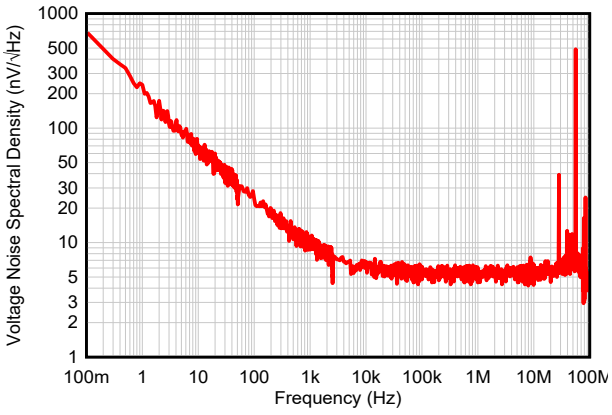

图 5-16. Input Voltage Noise Spectral Density vs Frequency

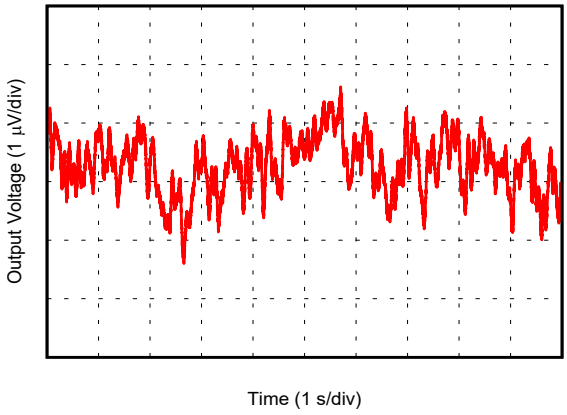

图 5-17. 0.1-Hz to 10-Hz Input Voltage Noise

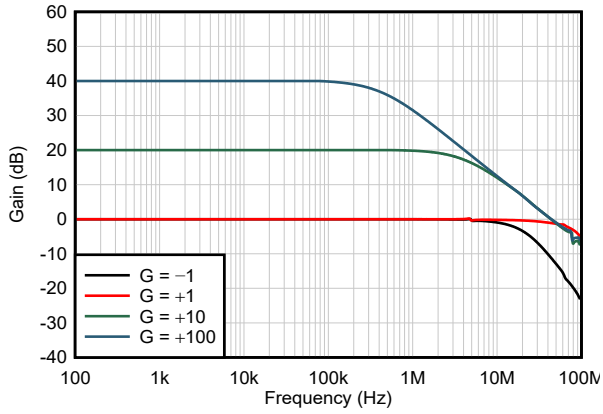

图 5-18. Closed-Loop Gain vs Frequency

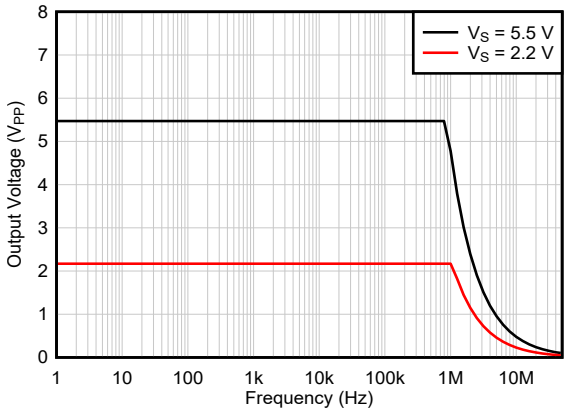

图 5-19. Maximum Output Voltage vs Frequency

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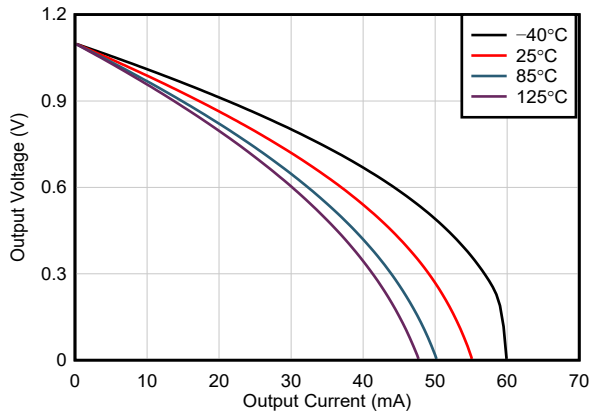
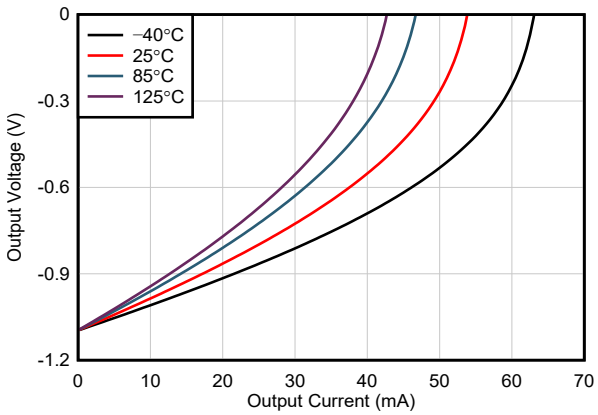
5.7 Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)



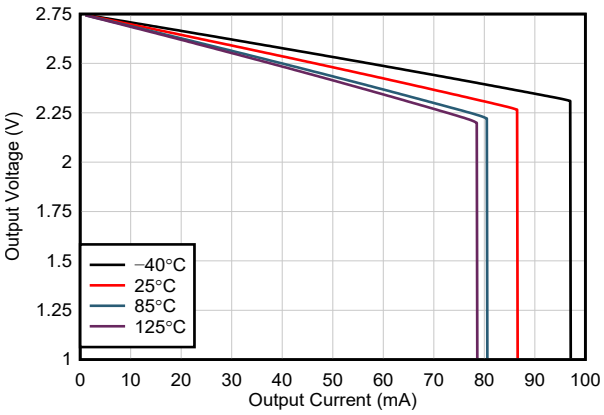
V_{V+} = 1.1 V, V_{V-} = – 1.1 V, current source load

图 5-20. Output Voltage Swing vs Output Current



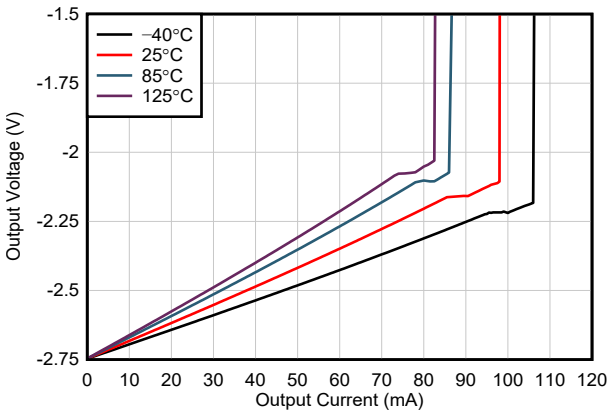
V_{V+} = 1.1 V, V_{V-} = – 1.1 V, current source load

图 5-21. Output Voltage Swing vs Output Current



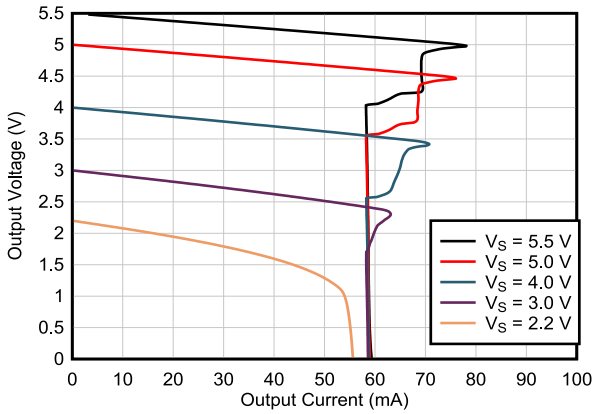
V_{V+} = 2.75 V, V_{V-} = – 2.75 V, current source load

图 5-22. Output Voltage Swing vs Output Current



V_{V+} = 2.75 V, V_{V-} = – 2.75 V, current source load

图 5-23. Output Voltage Swing vs Output Current



V_{V+} = 5.5 V, V_{V-} = 0 V, voltage source load

图 5-24. Output Voltage Swing vs Output Current

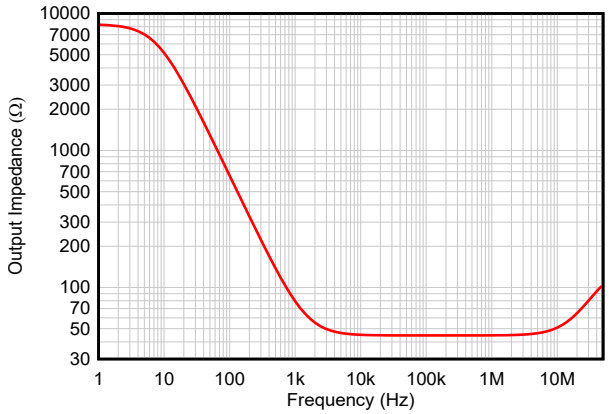


图 5-25. Open-Loop Output Impedance vs Frequency

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5.7 Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)

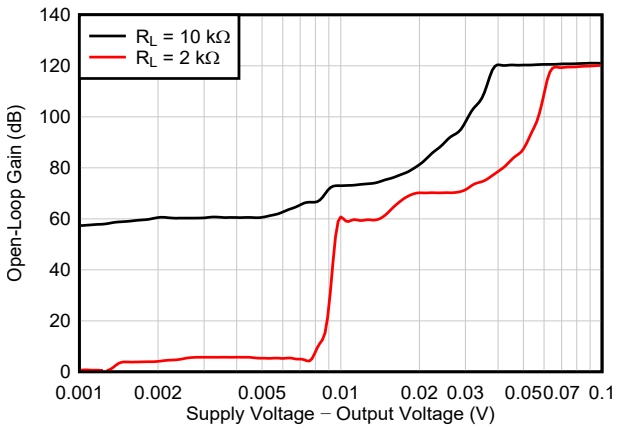
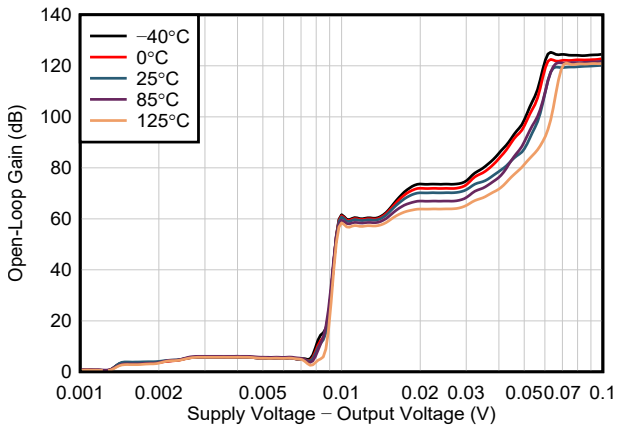
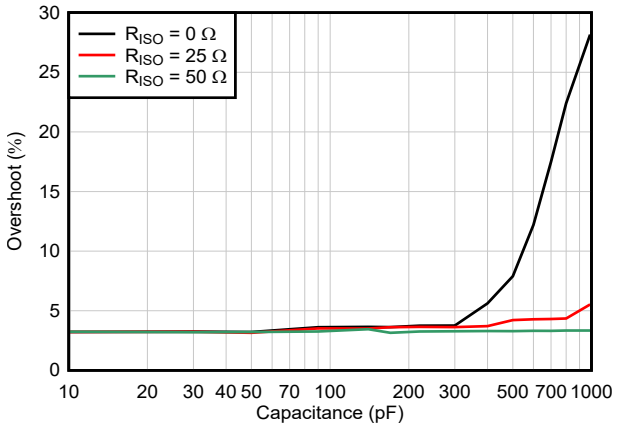


图 5-26. Open-Loop Gain vs Output to Supply Voltage Delta



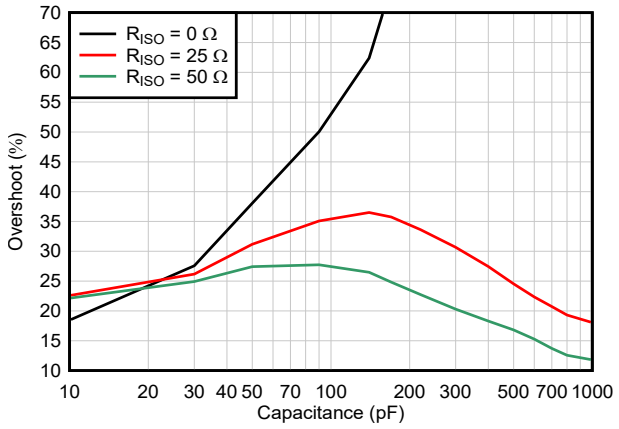
RL = 2 kΩ

图 5-27. Open-Loop Gain vs Output to Supply Voltage Delta



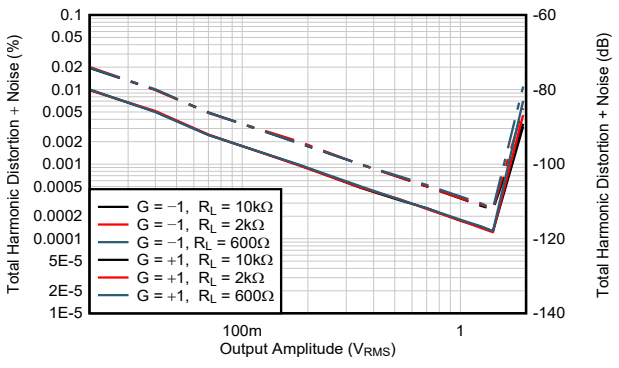
G = –1

图 5-28. Small-Signal Overshoot vs Load Capacitance



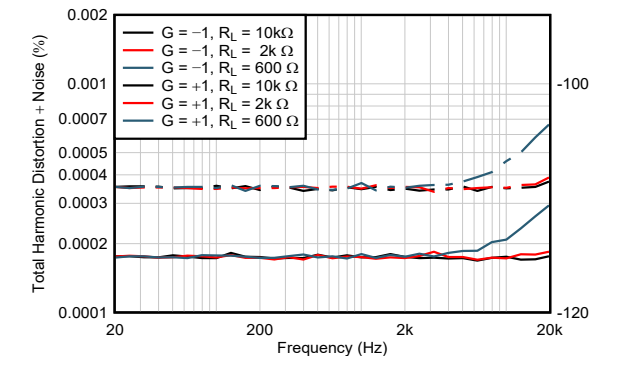
G = +1

图 5-29. Small-Signal Overshoot vs Load Capacitance



f = 1 kHz

图 5-30. THD+N vs Amplitude



VOUT = 1 VRMS

图 5-31. THD+N vs Frequency

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5.7 Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)

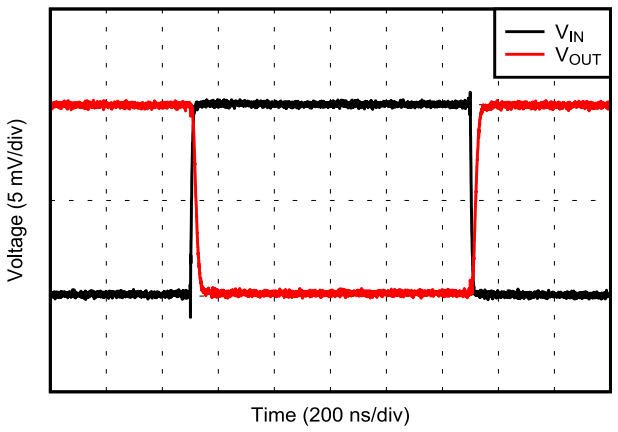

图 5-32. Small-Signal Step Response

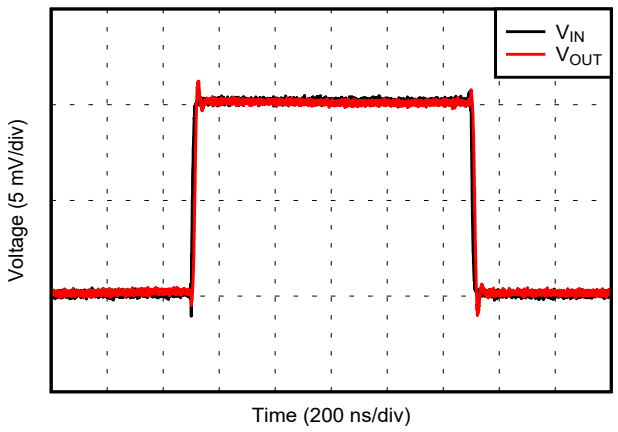

图 5-33. Small-Signal Step Response

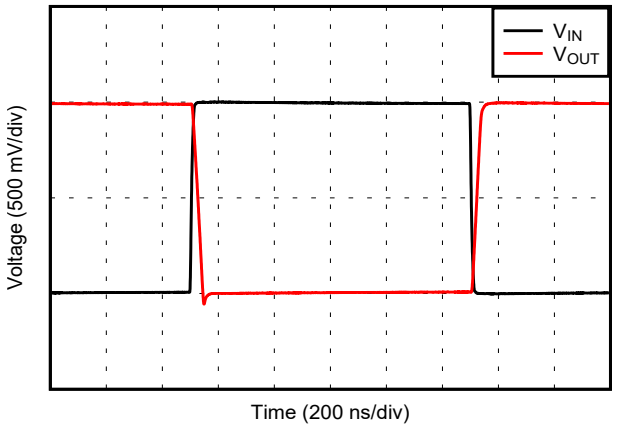

图 5-34. Large-Signal Step Response

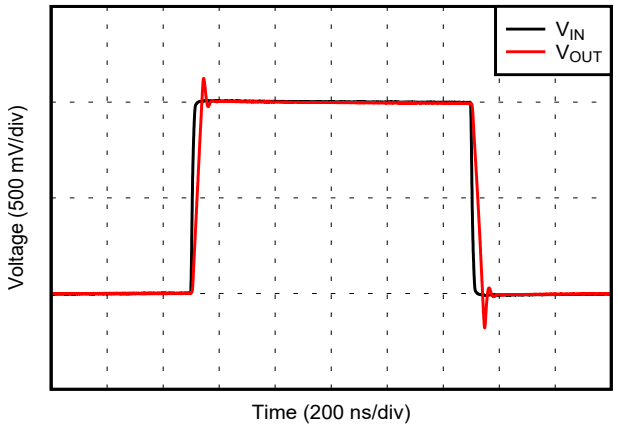

图 5-35. Large-Signal Step Response

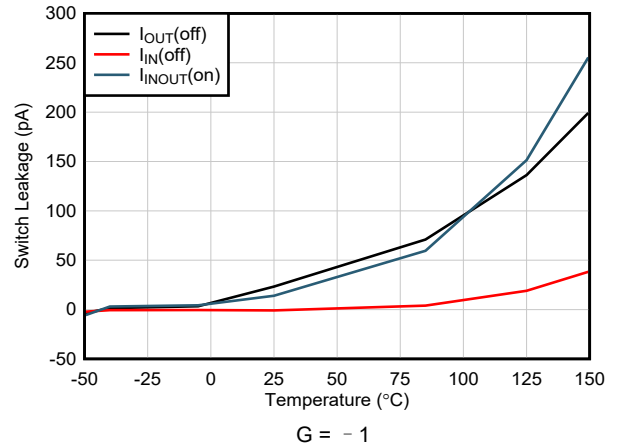

图 5-36. Switch Leakage Current vs Temperature

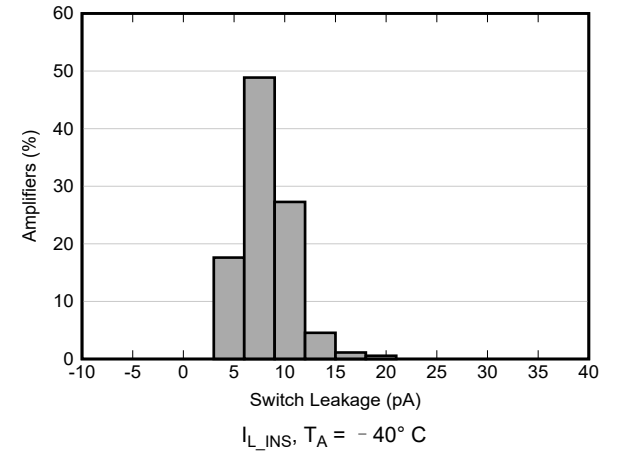

图 5-37. Switch Input Leakage Current Histogram

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5.7 Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)

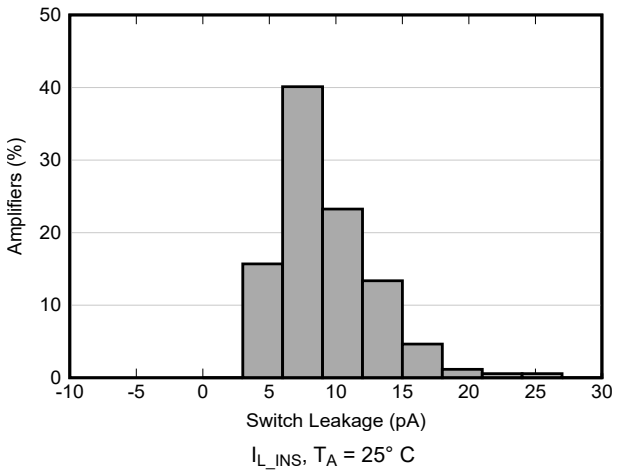

图 5-38. Switch Input Leakage Current Histogram

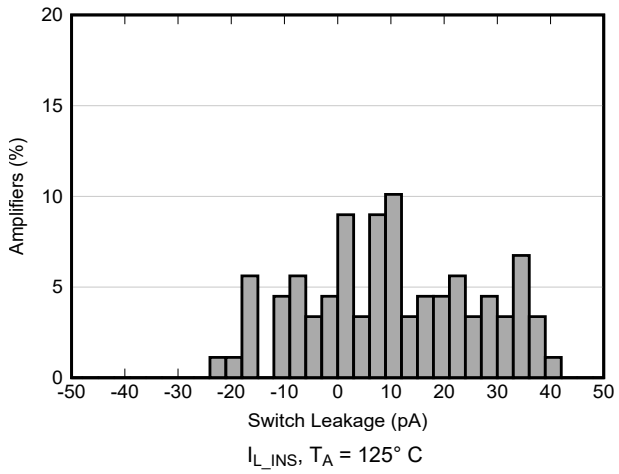

图 5-39. Switch Input Leakage Current Histogram

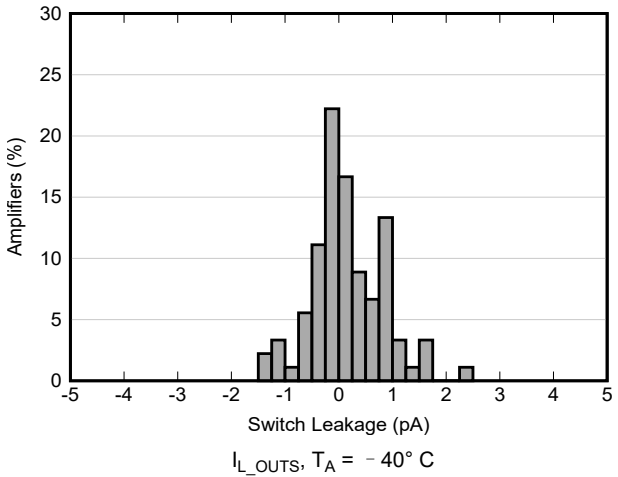

图 5-40. Switch Output Leakage Current Histogram

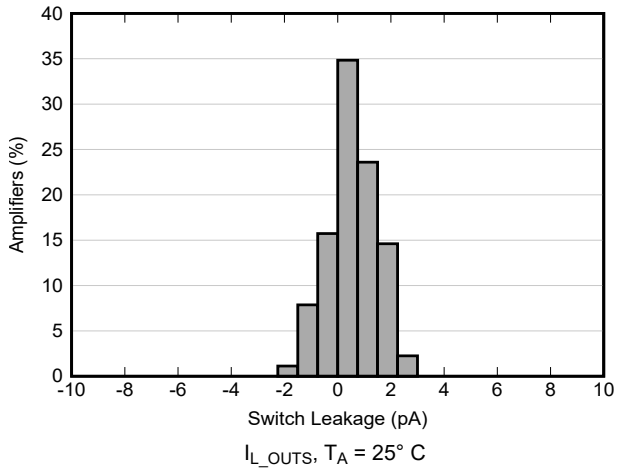

图 5-41. Switch Output Leakage Current Histogram

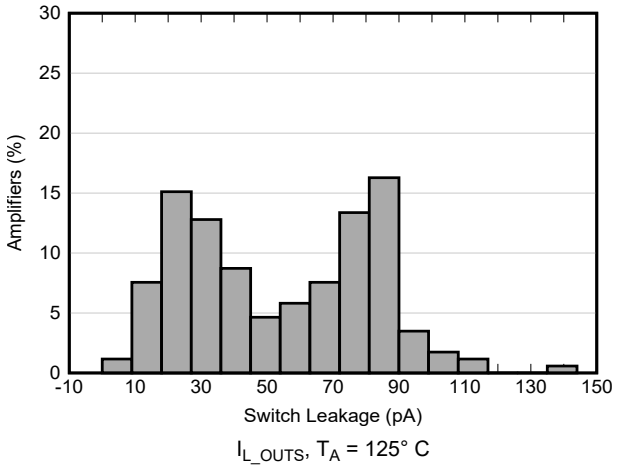

图 5-42. Switch Output Leakage Current Histogram

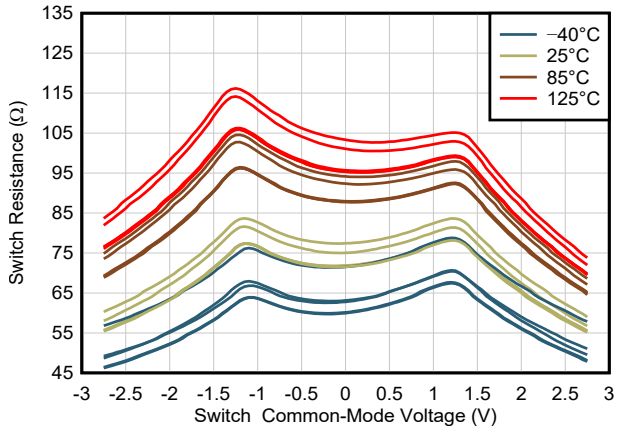

图 5-43. Switch On-Resistance vs Common-Mode Voltage

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5.7 Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, V_{CM} = V_{OUT} = mid-supply, C_L = 20 pF, and R_L = 10 kΩ (unless otherwise noted)

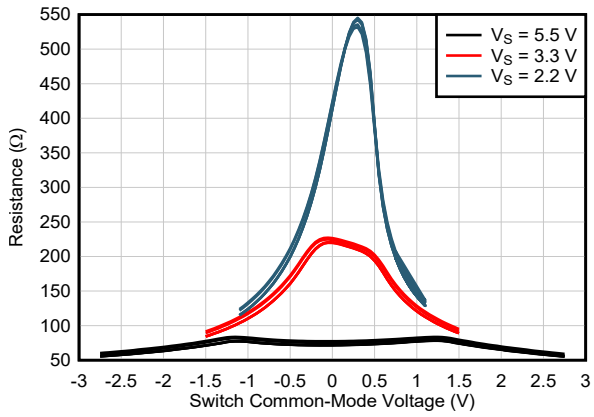

图 5-44. Switch On-Resistance vs Common-Mode Voltage

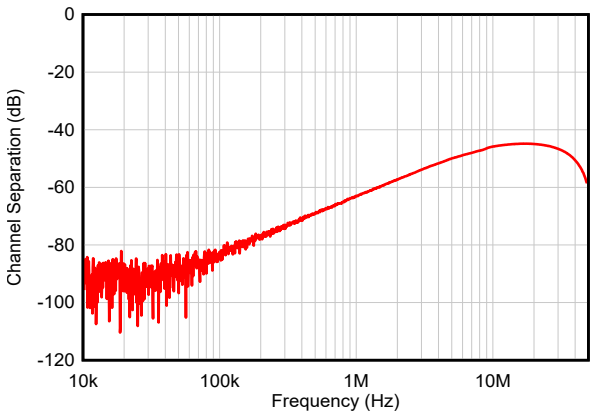

图 5-45. Switch Crosstalk vs Frequency

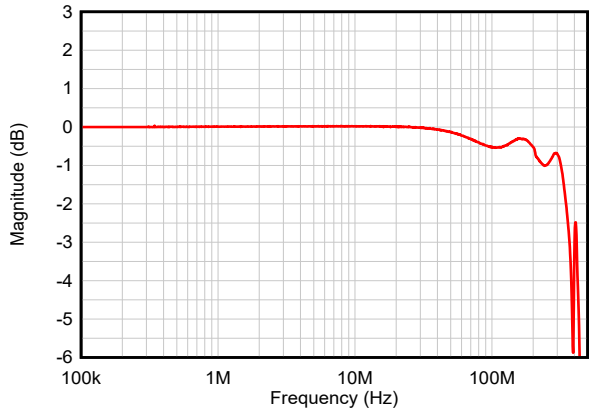

图 5-46. Switch Attenuation vs Frequency

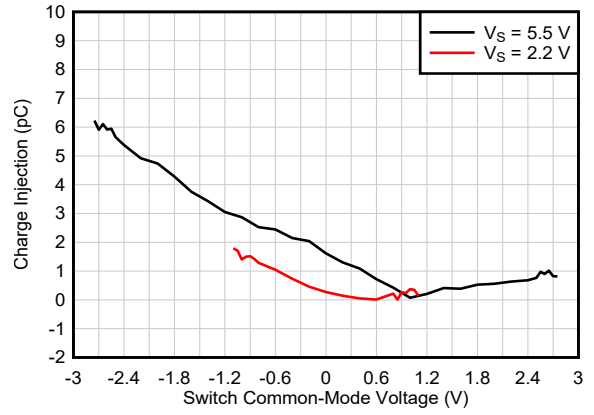

图 5-47. Switch Charge Injection vs Common-Mode Voltage

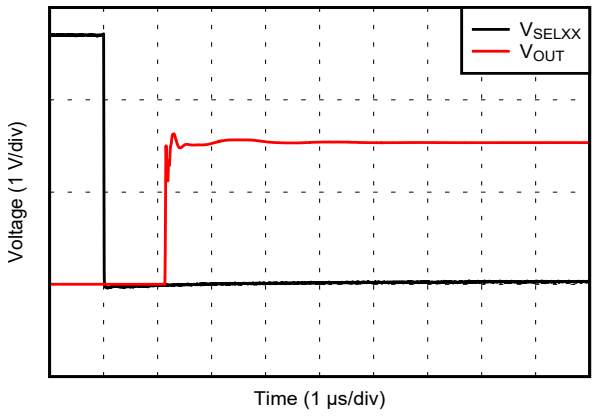

图 5-48. Switch Turn-on

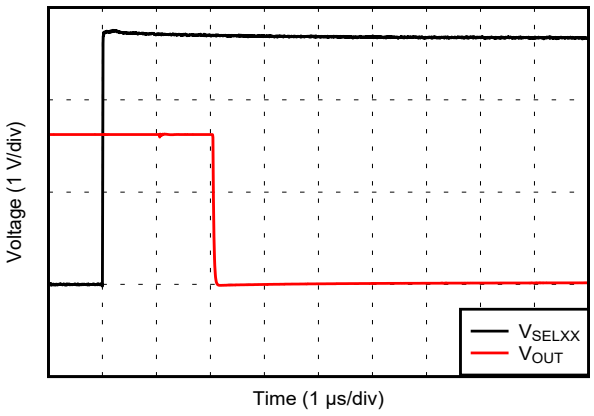

图 5-49. Switch Turn-off

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6 Parameter Measurement Information

6.1 Switch Characterization Configurations

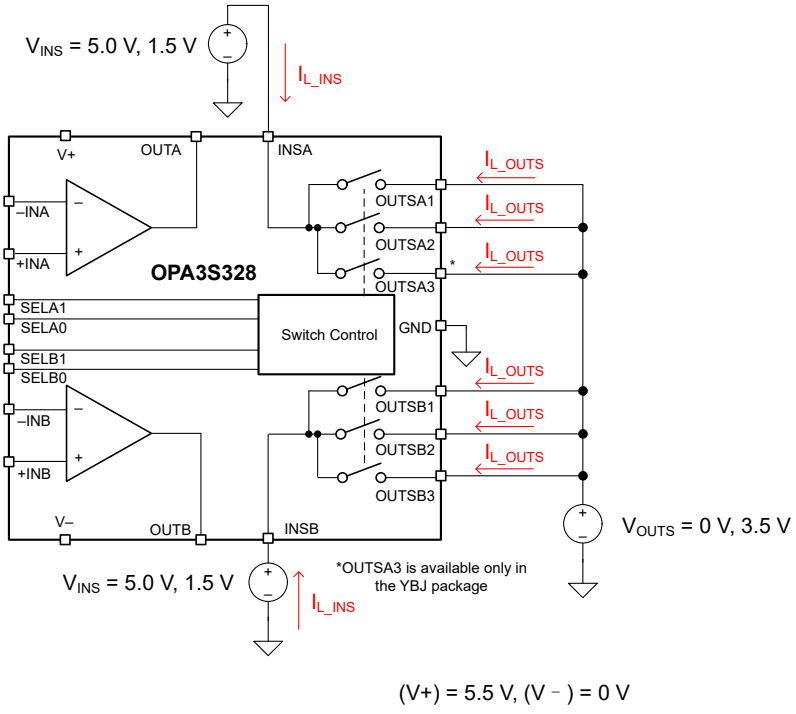

图 6-1. Switch Leakage Current, Open

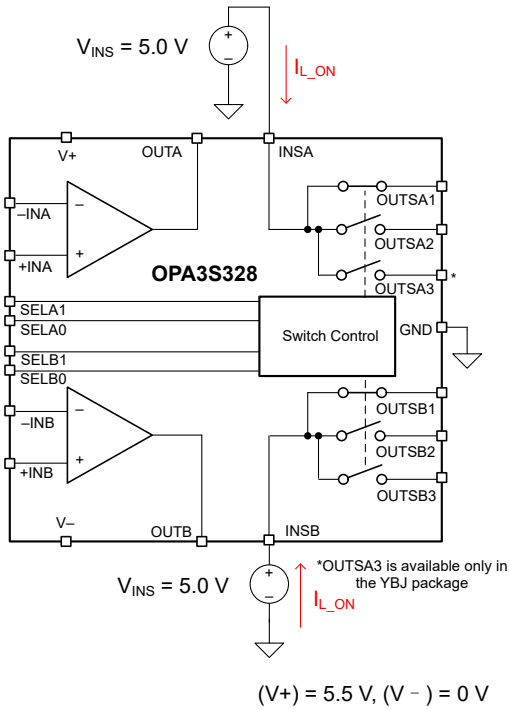

图 6-2. Switch Leakage Current, Closed

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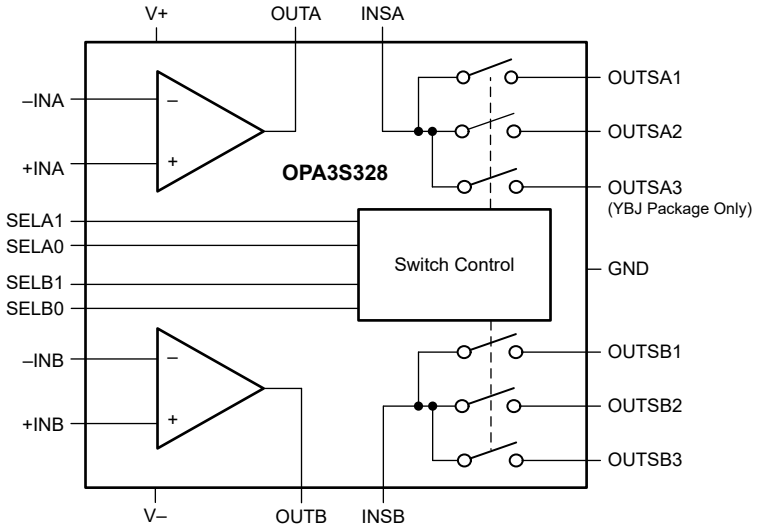
7 Detailed Description

7.1 Overview

The OPA3S328 features two high-speed, precision amplifiers combined with programmable switches that are designed to offer a compact sensor or optical interface for high resolution analog-to-digital converters (ADCs). Low output impedance with flat frequency characteristics and zero-crossover distortion circuitry enable high linearity over the full input common-mode range, achieving true rail-to-rail input from a 2.2-V to 5.5-V single supply. Integrated switches allow for multiple gain settings on a single amplifier stage without the need for an additional multiplexer device.

In addition to transimpedance applications, the OPA3S328 is flexible with many different application uses for a variety of equipment, such as optical modules, battery testers, medical instrumentation. This device can be used to replace larger transimpedance amplifiers, log amplifiers, programmable gain amplifiers, or programmable active filters.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Low Operating Voltage

The OPA3S328 amplifiers and switches operate on a single-supply voltage (2.2 V to 5.5 V), or a dual-supply voltage (±1.1 V to ±2.75 V), making these devices highly versatile, and easy to use with low supply rails. Use local bypass ceramic capacitors (typically, 0.001 µF to 0.1 µF) to ground on the power-supply pins, as well as a bypass capacitor connected between the positive and negative supply pins for dual-supply operation.

The digital input pins for switch and shutdown control (SELA0, SELA1, SELB0, SELB1) are referenced to the V+ supply for the positive rail, and to the digital ground (GND pin) for the negative rail. The GND pin can be forced to any voltage greater than V– and less than V+. However, the voltage between GND and V+ must be greater than the minimum requirement for the digital circuit block operation; see 节 7.4. For single-supply use cases, connect GND to V–.

The OPA3S328 amplifiers are fully specified from 2.2 V to 5.5 V and over the temperature range of –40°C to +125°C.

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7.3.2 Input and ESD Protection

The OPA3S328 incorporates internal electrostatic discharge (ESD) protection circuits on all pins. In the case of input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes also provide in-circuit input overdrive protection, provided that the current is limited to 10 mA. Many input signals are inherently current-limited to less than 10 mA; therefore, a limiting resistor is not required. 图 7-1 shows how a series input resistor (R_S) can be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input; therefore, keep this value to a minimum in noise-sensitive applications.

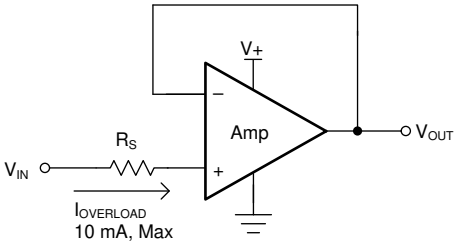

图 7-1. Input Current Protection

7.3.3 Programmable Switches

The OPA3S328 features integrated switches that can be used in many different configurations. Two sets of switches each have a single input (INSA and INSB) that multiplexes to two or three different outputs (OUTSA1, 2, and 3 and OUTSB1, 2, and 3). The QFN package has both a 1-to-2 switch matrix and a 1-to-3 switch matrix. The DSBGA package has two 1-to-3 switch matrices. The switches feature *make-before-break* switching, meaning that when programmed to a different switch connection, the previous switch does not change to high-impedance state until the new switch is closed, with a typical 2-µs delay when both switches are closed. This feature keeps the amplifier from operating in an open-loop state when the switches are used in a switched-gain transimpedance configuration.

7.3.4 Rail-to-Rail Input

The OPA3S328 features true rail-to-rail input operation, with supply voltages as low as ±1.1 V (2.2 V). The design of the OPA3S328 amplifiers include an internal charge-pump that powers the amplifier input stage with an internal supply rail at approximately 1.6 V greater than the external supply (V_{S+}). This internal supply rail allows the single differential input pair to operate and remain very linear over a very-wide input common-mode range. A unique zero-crossover input topology eliminates the input offset transition region typical of many rail-to-rail, complementary-input-stage, operational amplifiers. This topology allows the OPA3S328 to provide excellent common-mode performance (CMRR > 120 dB, typical) over the entire common-mode input range, which extends 100 mV beyond both power-supply rails. When driving analog-to-digital converters (ADCs), the highly linear V_{CM} range of the OPA3S328 provides maximum linearity and lowest distortion.

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7.3.5 Phase Reversal

The OPA3S328 op amps are designed to be immune to phase reversal when the input pins exceed the supply voltages, and thus provide further in-system stability and predictability. 图 7-2 shows the input voltage exceeding the supply voltage without any phase reversal.

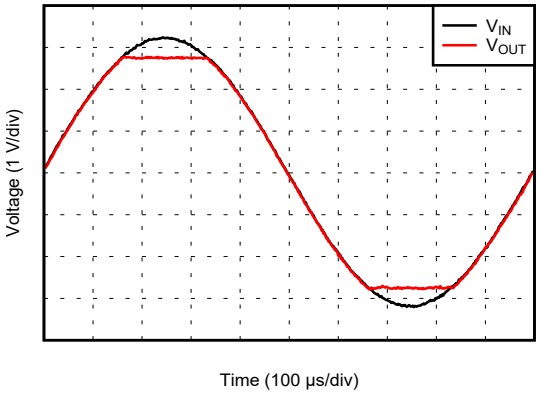

图 7-2. No Phase Reversal

7.4 Device Functional Modes

The OPA3S328 is specified to operate when power-supply voltages are between 2.2 V to 5.5 V (single-ended). Each amplifier can also be placed in power-down mode, as described in the in the following subsection.

7.4.1 Power-Down Mode

The OPA3S328 amplifiers can be placed into a power-down state independently. When in this power-down state, the output of the amplifier is high-impedance (> 1 GΩ) and the amplifier consumes 30 µA of quiescent current.

Power down is controlled through digital logic pins SELA0, SELA1, SELB0 and SELB1, which require a minimum 1.8 V between V+ and GND to provide functionality. For guidance on programming the device for power down, see the logic table in 表 4-3.

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8 Application and Implementation

备注

以下应用部分中的信息不属于 TI 器件规格的范围，TI 不担保其准确性和完整性。TI 的客 户应负责确定器件是否适用于其应用。客户应验证并测试其设计，以确保系统功能。

8.1 Application Information

The OPA3S328 offers a unique combination of two outstanding dc and ac performance amplifiers, along with integrated low-leakage switches. This combination of devices can be configured in a variety of ways in many different circuit blocks, such as switched-gain transimpedance amplifiers, switched-gain voltage amplifiers, programmable frequency active filters, and flexible analog-to-digital converter front ends.

8.1.1 Capacitive Load and Stability

The OPA3S328 is designed to be used in high-speed applications for TIA and ADC input-driving amplifiers. As with all op amps, there can be specific instances where the OPA3S328 becomes unstable. The particular op-amp circuit configuration, layout, gain, and output loading are some of the factors to consider when establishing whether an amplifier is stable in operation. An op amp in the unity-gain (1-V/V) buffer configuration and driving a capacitive load exhibits a greater tendency to become unstable than an amplifier operated at a higher noise gain, as seen in 图 5-29. The capacitive load, in conjunction with the op amp output resistance, creates a pole within the feedback loop that degrades the phase margin. The degradation of the phase margin increases as the capacitive loading increases. When operating in the unity-gain configuration, the OPA3S328 remains stable with a pure capacitive load up to 100 pF.

One technique to increase the capacitive load drive capability of an amplifier operating in a unity-gain configuration is to insert a small resistor (R_S), typically 10 Ω to 50 Ω, in series with the output. 图 8-1 shows this technique. This resistor significantly reduces the overshoot and ringing associated with large capacitive loads.

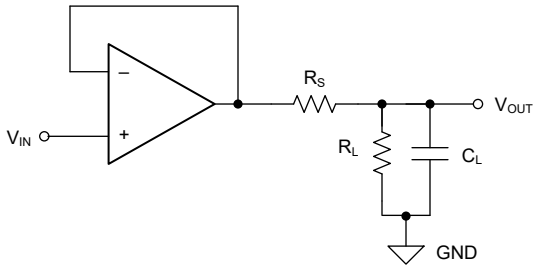

图 8-1. Improving Capacitive Load Drive

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8.1.2 EMI Susceptibility and Input Filtering

Operational amplifiers vary in susceptibility to electromagnetic interference (EMI). If conducted EMI enters the operational amplifier, the dc offset observed at the amplifier output can shift from the nominal value while EMI is present. This shift is a result of signal rectification associated with the internal semiconductor junctions. While all operational amplifier pin functions can be affected by EMI, the input pins are most likely susceptible. The OPA3S328 operational amplifiers incorporate an internal input low-pass filter that reduces the amplifiers response to EMI. Both common-mode and differential-mode filtering are provided by the input filter. 图 8-2 shows the amplifier EMIRR response.

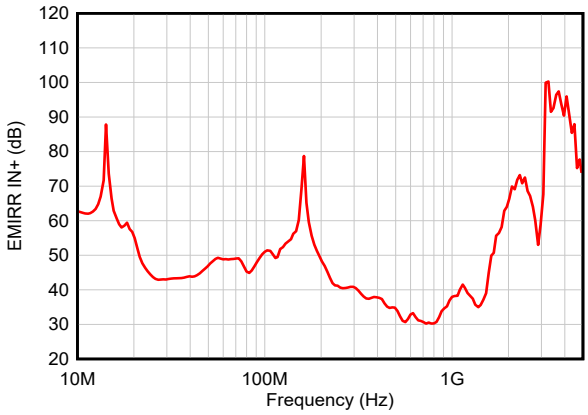


图 8-2. OPA3S328 EMIRR Response

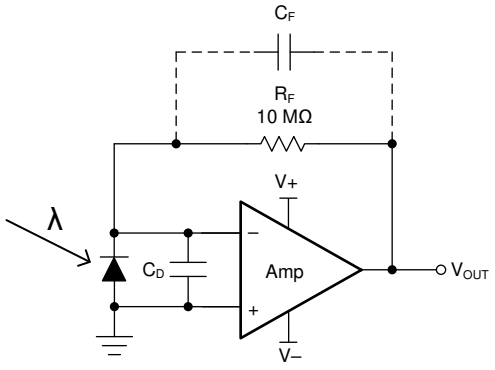
8.1.3 Transimpedance Amplifier

Wide gain bandwidth, low-input bias current, low input voltage, and current noise make the OPA3S328 an excellent wideband photodiode transimpedance amplifier. Low-voltage noise is important because photodiode capacitance causes the effective noise gain of the circuit to increase at high frequency.

图 8-3 shows the key elements to a transimpedance design, which are:

- expected diode capacitance (C_D); include the parasitic input common-mode voltage and differential-mode input capacitance
- desired transimpedance gain (R_F)
- gain-bandwidth (GBW) for the OPA3S328 (40 MHz)

With these three variables set, the feedback capacitor value (C_F) can be set to control the frequency response. C_F includes the stray capacitance of R_F, which is 0.2 pF for a typical surface-mount resistor.



NOTE: C_F is optional to prevent gain peaking, and includes the stray capacitance of R_F.

图 8-3. Dual-Supply Transimpedance Amplifier

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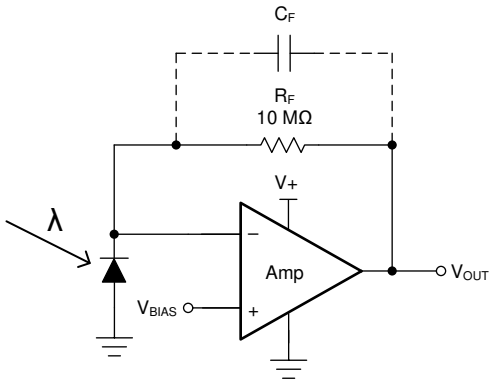
For optimized frequency response, set the feedback pole as follows:

$$\frac{1}{2\pi R_F C_F} = \sqrt{\frac{GBW}{4\pi R_F C_D}} \quad (1)$$

方程式 2 calculates the bandwidth.

$$f_{-3dB} = \sqrt{\frac{GBW}{2\pi R_F C_D}} \quad (Hz) \quad (2)$$

For single-supply applications, the +IN input can be biased with a positive dc voltage to allow the output to reach true zero when the photodiode is not exposed to any light, and respond without the added delay that results from coming out of the negative rail. 图 8-4 shows this configuration. This bias voltage also appears across the photodiode, providing a reverse bias for faster operation.



NOTE: C_F is optional to prevent gain peaking, and includes the stray capacitance of R_F.

图 8-4. Single-Supply Transimpedance Amplifier

For more information, see the *Compensate Transimpedance Amplifiers Intuitively* and *Build a Programmable Gain Transimpedance Amplifier Using the OPA3S328* application reports.

8.1.3.1 Optimizing the Transimpedance Circuit

To achieve the best performance, select components according to the following guidelines:

1. For the lowest noise, select R_F to create the total required gain. A lower value for R_F and adding gain after the transimpedance amplifier generally produces poorer noise performance. The noise produced by R_F increases with the square-root of R_F; whereas, the signal increases linearly. Therefore, signal-to-noise ratio improves when all the required gain is placed in the transimpedance stage.
2. Minimize photodiode capacitance and stray capacitance at the summing junction (inverting input). This capacitance causes the op-amp voltage noise to be amplified (increased amplification at high frequency). Use a low-noise voltage source to reverse-bias a photodiode to significantly reduce capacitance. Smaller photodiodes have lower capacitance. Use optics to concentrate light on a small photodiode.
3. Noise increases with increased bandwidth. Limit the circuit bandwidth to only that required. Use a capacitor across the R_F to limit bandwidth, even if not required for stability.
4. Circuit board leakage can degrade the performance of an otherwise well-designed amplifier. Clean the circuit board carefully. A circuit-board guard trace that encircles the summing junction and is driven at the same voltage helps to control leakage.

For more information, see the *Noise Analysis of FET Transimpedance Amplifiers* and the *Noise Analysis for High-Speed Op Amps* application reports.

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8.2 Typical Application

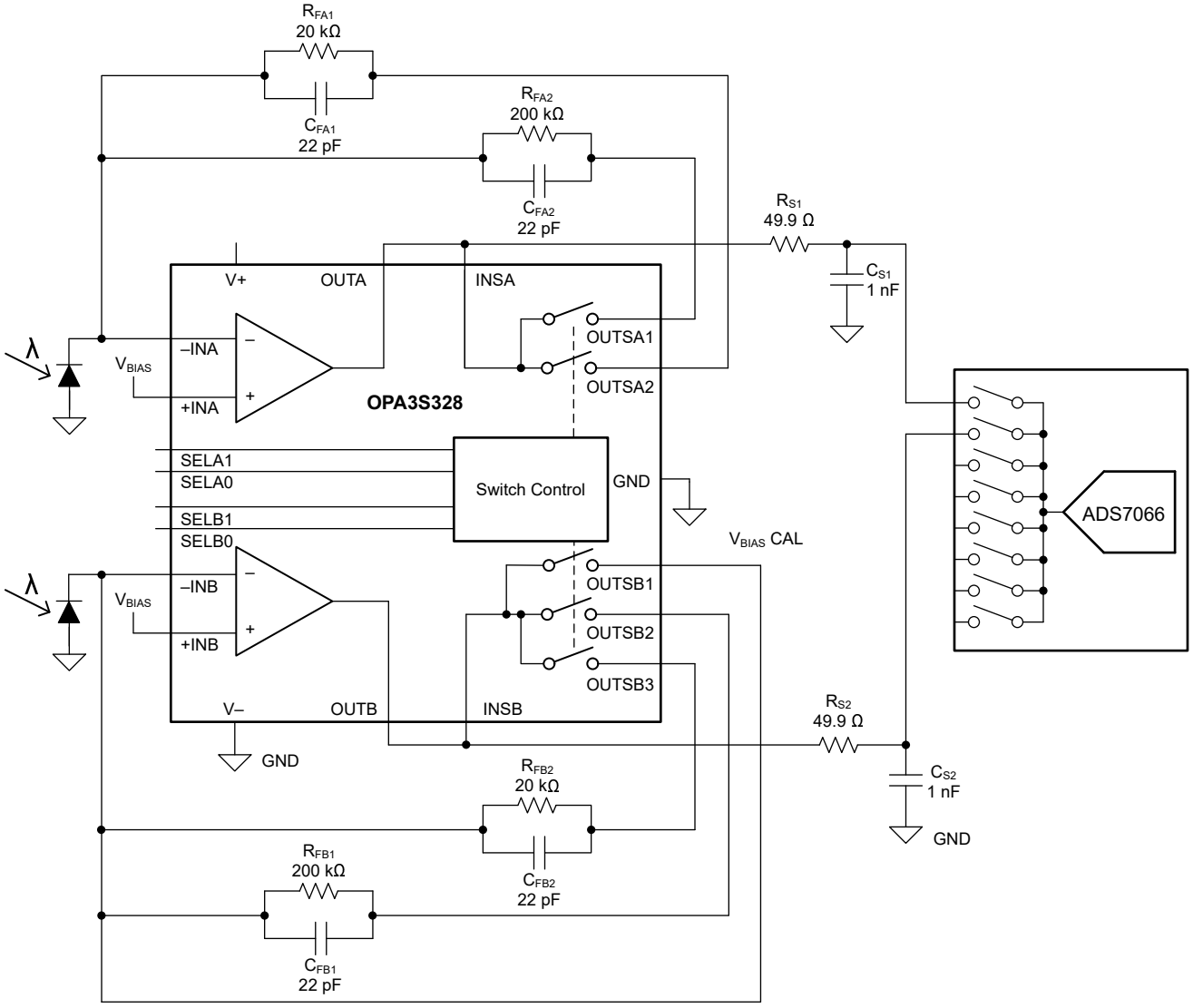

图 8-5. Dual Transimpedance Front End With Gain Switching

8.2.1 Design Requirements

- Gain = 0.02 V/µA and 0.2 V/µA
- Low-pass cutoff frequency = 36 kHz
- 1% accuracy from 10 nA to 100 µA

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8.2.2 Detailed Design Procedure

- Select transimpedance gains to align the measurement current range within the range of the ADC. For the ADS7066, the input range is programmed to 5 V. Using this configuration, the peak current range is calculated by dividing the input range by the feedback resistor, R_{FB}, which yields 25 μA for a 200-kΩ resistor and 250 μA for a 20-kΩ feedback resistor.
- The current measurement LSB size is 5 V / (R_F × 65536). The result yields 381 pA resolution for a 200-kΩ feedback resistor, and 3.81 nA resolution for a 20-kΩ resistor.
- A dc voltage is used on the noninverting pin of the amplifier for two important reasons. The first reason is to reverse-bias the photodiode, which helps reduce photodiode capacitance and makes sure the photodiode does not operate in a forward-bias state. The second reason is to keep the output voltage of the amplifier from coming too close to the negative supply (V–) voltage when the input current is zero. If the output voltage comes within approximately 40 mV (assuming a 10-kΩ load), the amplifier enters a saturation state, which results in loss of open-loop gain and slow transient response to exit the state (overload recovery). Typically 100 mV is enough to make sure that the amplifier does not saturate.
- A feedback capacitor can be used to help the stability of the circuit. Typically, if the feedback capacitor has a higher capacitance than the total input capacitance, advanced compensation schemes are not necessary to maintain stability of the amplifier along with the capacitance of the photodiode. This configuration can limit the usable bandwidth of the circuit; see 节 8.1.3.1 for further details.

8.2.3 Application Curve

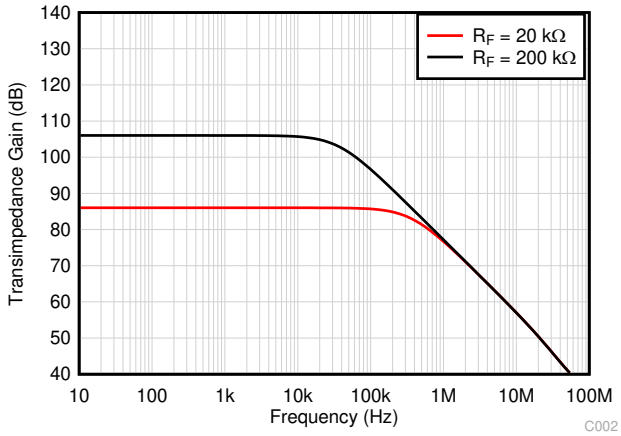

图 8-6. OPA3S328 Transimpedance Gain

8.3 Power Supply Recommendations

The OPA3S328 is specified for operation from 2.2 V to 5.5 V (±1.1 V to ±2.75 V), and many specifications apply from –40°C to +125°C.

> **小心**
>
> Supply voltages larger than 6 V can permanently damage the device; see 节 5.1.

Place 0.1-μF bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see 节 8.4.

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8.4 Layout

8.4.1 Layout Guidelines

The OPA3S328 contains two wideband amplifiers and an integrated charge pump. To realize the full operational performance of the device and remove the noise from the charge pump circuit, good high-frequency PCB layout practices must be employed. The bypass capacitors must be connected between each supply pin and ground as close to the device as possible. Additionally, in dual-supply systems, there must be a ceramic bypass capacitor between the supply pins. Use bypass capacitor traces designed for minimum inductance.

8.4.2 Layout Example

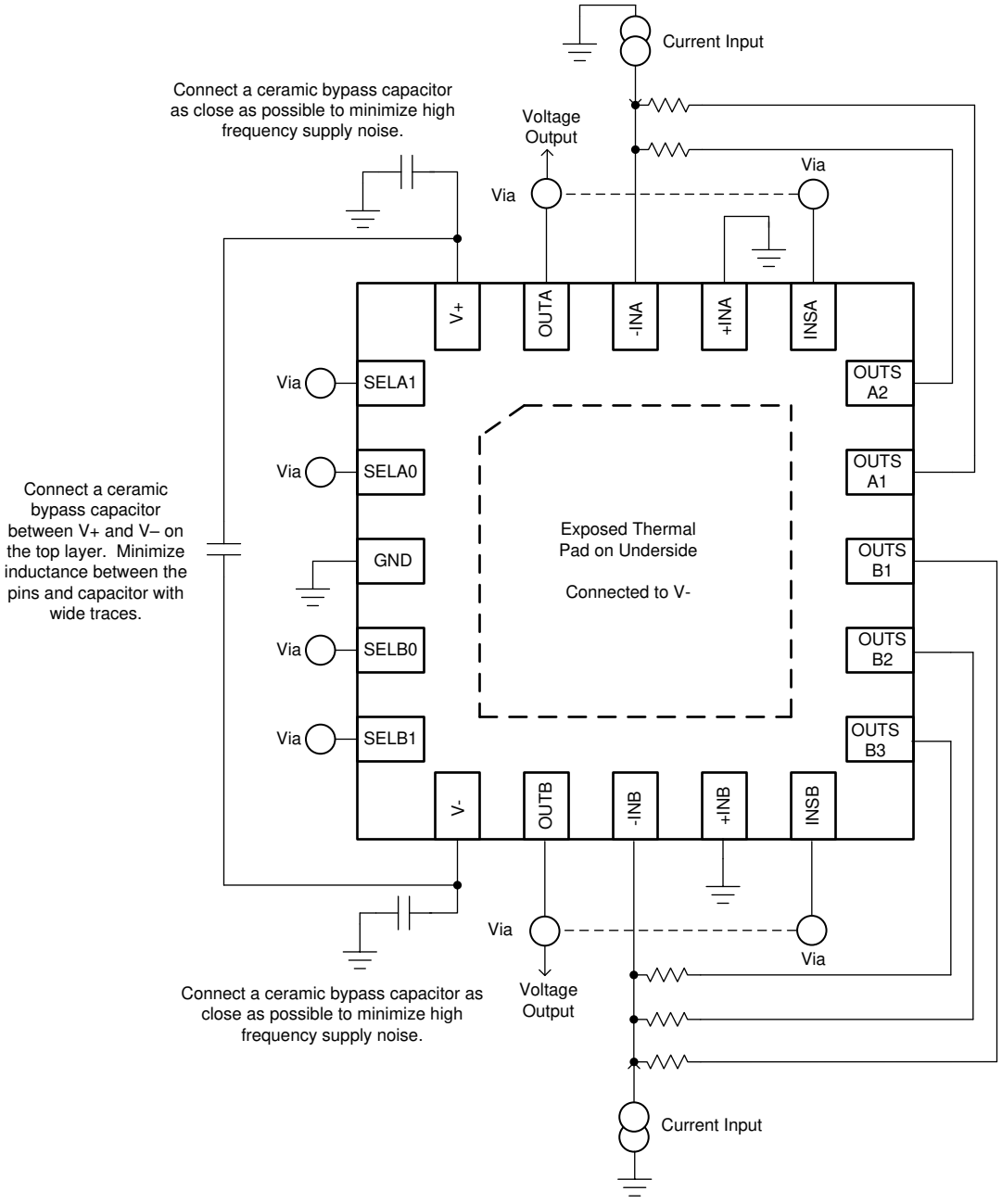

图 8-7. Layout Example

9 Device and Documentation Support

9.1 Device Support

9.1.1 Development Support

9.1.1.1 PSpice® for TI

PSpice® for TI 是可帮助评估模拟电路性能的设计和仿真环境。在进行布局和制造之前创建子系统设计和原型解决方案，可降低开发成本并缩短上市时间。

9.1.1.2 TINA-TI™ 仿真软件（免费下载）

TINA-TI™ 仿真软件是一款简单易用、功能强大且基于 SPICE 引擎的电路仿真程序。TINA-TI 仿真软件是 TINA™ 软件的一款免费全功能版本，除了一系列无源和有源模型外，此版本软件还预先载入了一个宏模型库。TINA-TI 仿真软件提供所有传统的 SPICE 直流、瞬态和频域分析，以及其他设计功能。

TINA-TI 仿真软件提供全面的后处理能力，便于用户以多种方式获得结果，用户可从设计工具和仿真网页免费下载。虚拟仪器提供选择输入波形和探测电路节点、电压以及波形的能力，从而构建一个动态的快速启动工具。

备注

必须安装 TINA 软件或者 TINA-TI 软件后才能使用这些文件。请从 TINA-TI™ 软件文件夹中下载免费的 TINA-TI 仿真软件。

9.1.1.3 TI 参考设计

TI 参考设计是由 TI 的精密模拟应用专家创建的模拟解决方案。TI 参考设计提供了许多实用电路的工作原理、组件选择、仿真、完整印刷电路板 (PCB) 电路原理图和布局布线、物料清单以及性能测量结果。TI 参考设计可在线获取，网址为 https://www.ti.com/reference-designs。

9.1.1.4 滤波器设计工具

滤波器设计工具是一款简单、功能强大且便于使用的有源滤波器设计程序。利用滤波设计器，用户可使用精选 TI 运算放大器和 TI 供应商合作伙伴提供的无源器件来打造理想滤波器设计方案。

设计工具和仿真网页以基于网络的工具形式提供滤波设计工具。用户通过该工具可在短时间内完成多级有源滤波器解决方案的设计、优化和仿真。

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9.2 Documentation Support

9.2.1 Related Documentation

The following documents are relevant to using the OPA3S328, and recommended for reference. All are available for download at www.ti.com (unless otherwise noted):

- Texas Instruments, *PM2.5/PM10 Particle Sensor Analog Front-End for Air Quality Monitoring Design*
- Texas Instruments, *QFN/SON PCB Attachment*
- Texas Instruments, *Quad Flatpack No-Lead Logic Packages*
- Texas Instruments, *Compensate Transimpedance Amplifiers Intuitively*
- Texas Instruments, *Noise Analysis of FET Transimpedance Amplifiers*
- Texas Instruments, *Noise Analysis for High-Speed Op Amps*
- Texas Instruments, *Build a Programmable Gain Transimpedance Amplifier Using the OPA3S328*

9.3 接收文档更新通知

要接收文档更新通知，请导航至 ti.com 上的器件产品文件夹。点击*通知* 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

9.4 支持资源

TI E2E™ 中文支持论坛是工程师的重要参考资料，可直接从专家处获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题，获得所需的快速设计帮助。

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静电放电 (ESD) 会损坏这个集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理和安装程序，可能会损坏集成电路。

ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

9.7 术语表

TI 术语表　　本术语表列出并解释了术语、首字母缩略词和定义。

10 Revision History

注：以前版本的页码可能与当前版本的页码不同

Changes from Revision C (August 2023) to Revision D (December 2023)	Page
• 将 OPA3S328 YBJ（DSBGA，24）封装状态从预告信息（样片预发布）更改为量产数据（正在供货）	1

Changes from Revision B (November 2021) to Revision C (August 2023)	Page
• 将 OPA3S328 YBJ（DSBGA，24）封装状态从预发布（无样片）更改为预告信息（样片预发布）	1
• Changed the ESD rating to the bidirectional value	5
• Changed open-loop output impedance symbol from Ro to Zo	6

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Changes from Revision A (September 2021) to Revision B (November 2021)	Page
• Changed YBJ preview Figure 5-2 to correct pin configuration	3

Changes from Revision * (October 2020) to Revision A (September 2021)	Page
• 将 OPA3S328 RGR (VQFN-20) 封装状态从预告信息（预发布）更改为量产数据（正在供货）	1

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
OPA3S328RGRR	ACTIVE	VQFN	RGR	20	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	O3S328	Samples
OPA3S328RGRT	ACTIVE	VQFN	RGR	20	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	O3S328	Samples
OPA3S328YBJR	ACTIVE	DSBGA	YBJ	24	3000	RoHS & Green	SNAGCU	Level-1-260C-UNLIM	-40 to 125	OPA3S328	Samples
XOPA3S328YBJR	ACTIVE	DSBGA	YBJ	24	3000	TBD	Call TI	Call TI	-40 to 125		Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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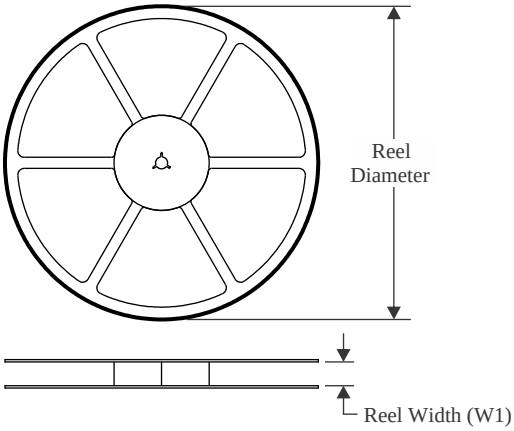
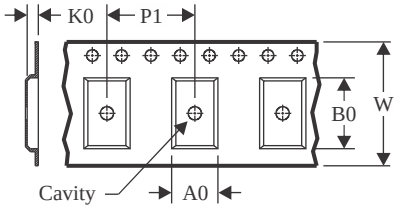
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

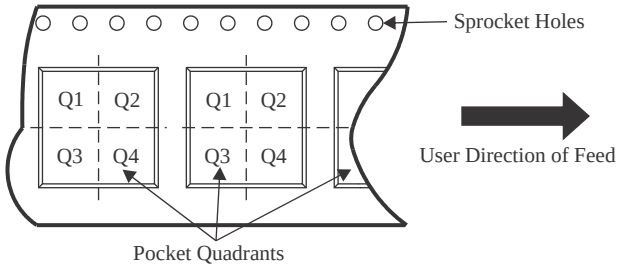


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

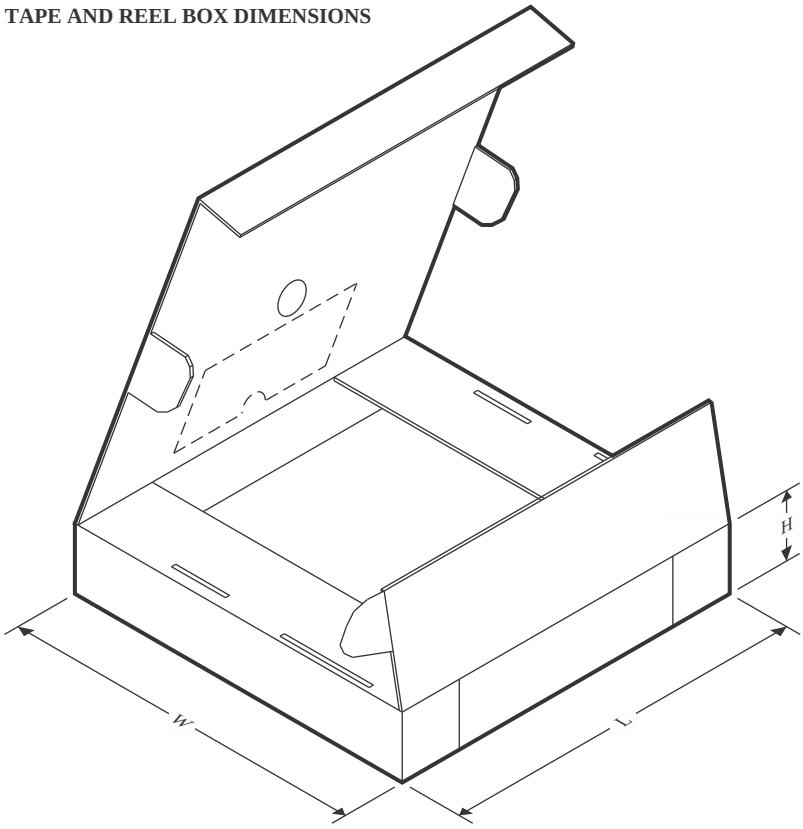
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
OPA3S328RGRR	VQFN	RGR	20	3000	330.0	12.4	3.75	3.75	1.15	8.0	12.0	Q2
OPA3S328RGRT	VQFN	RGR	20	250	180.0	12.4	3.75	3.75	1.15	8.0	12.0	Q2
OPA3S328YBJR	DSBGA	YBJ	24	3000	180.0	8.4	2.24	2.24	0.45	4.0	8.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
OPA3S328RGRR	VQFN	RGR	20	3000	367.0	367.0	35.0
OPA3S328RGRT	VQFN	RGR	20	250	210.0	185.0	35.0
OPA3S328YBJR	DSBGA	YBJ	24	3000	182.0	182.0	20.0

GENERIC PACKAGE VIEW

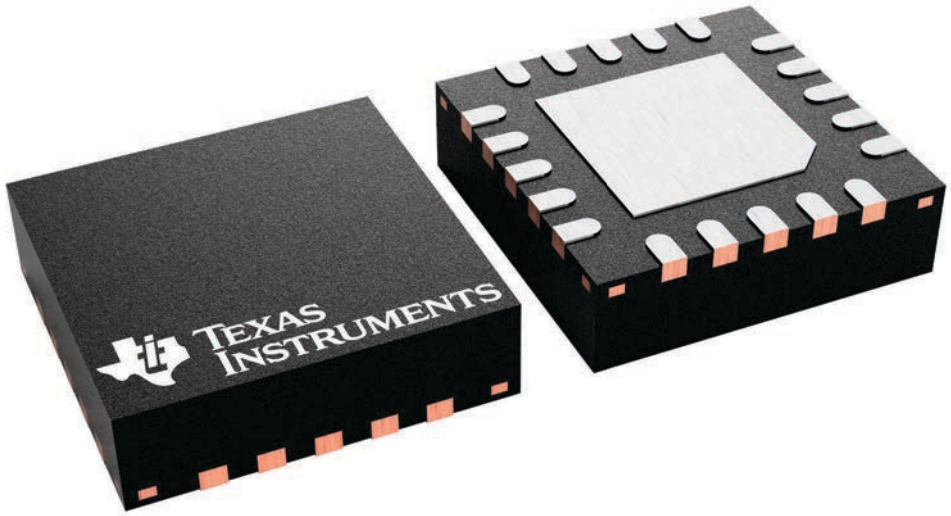
RGR 20

VQFN - 1 mm max height

3.5 x 3.5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



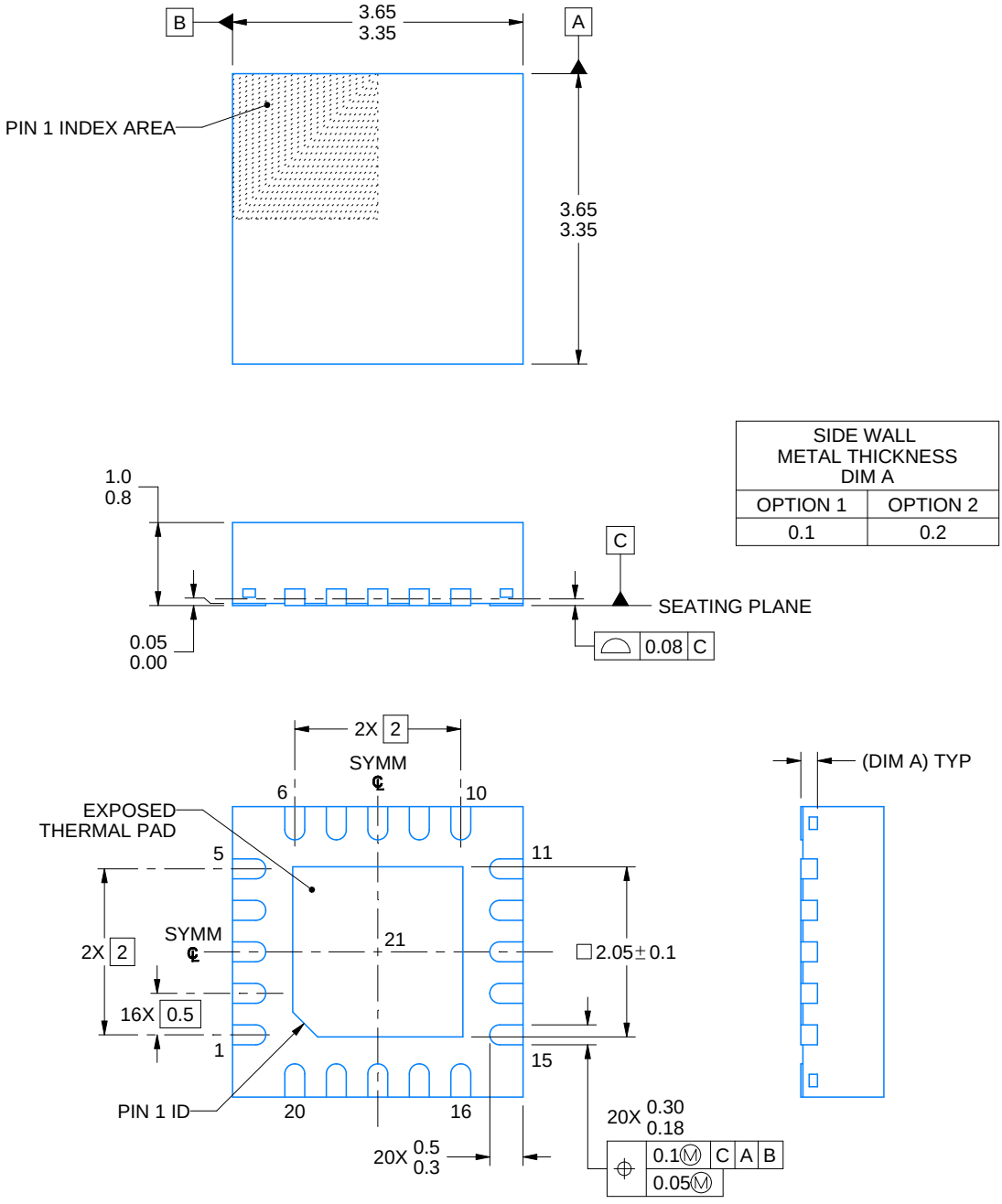
4228482/A

PACKAGE OUTLINE

RGR0020A

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



SIDE WALL METAL THICKNESS DIM A	
OPTION 1	OPTION 2
0.1	0.2

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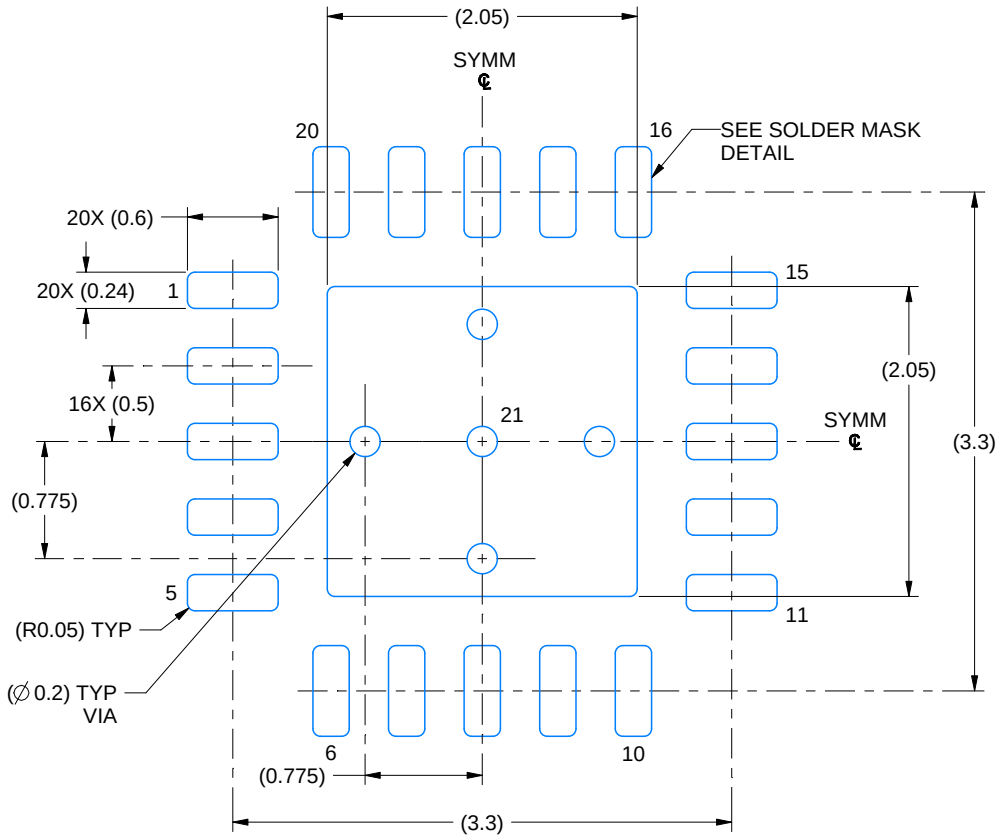
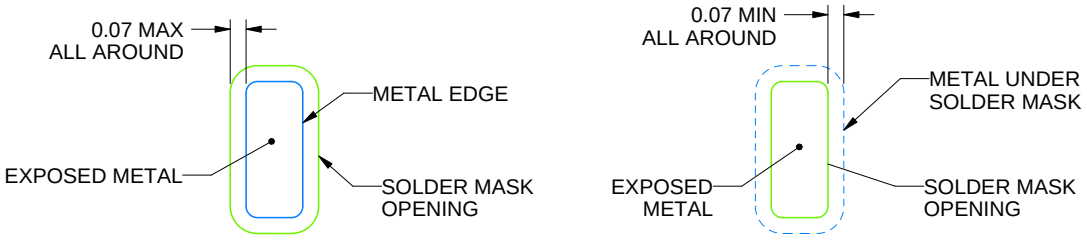
NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 20X



SOLDER MASK DETAILS

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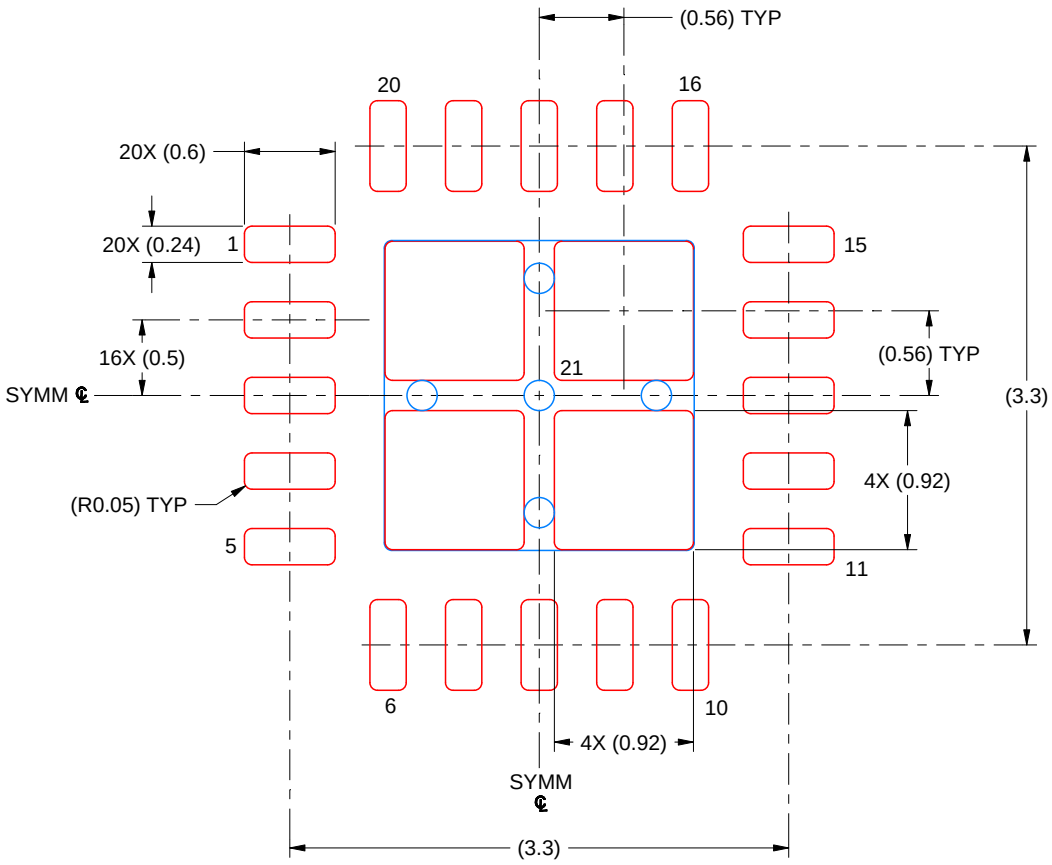
NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



SOLDER PASTE EXAMPLE
BASED ON 0.125 MM THICK STENCIL
SCALE: 20X

EXPOSED PAD 21
81% PRINTED SOLDER COVERAGE BY AREA UNDER PACKAGE

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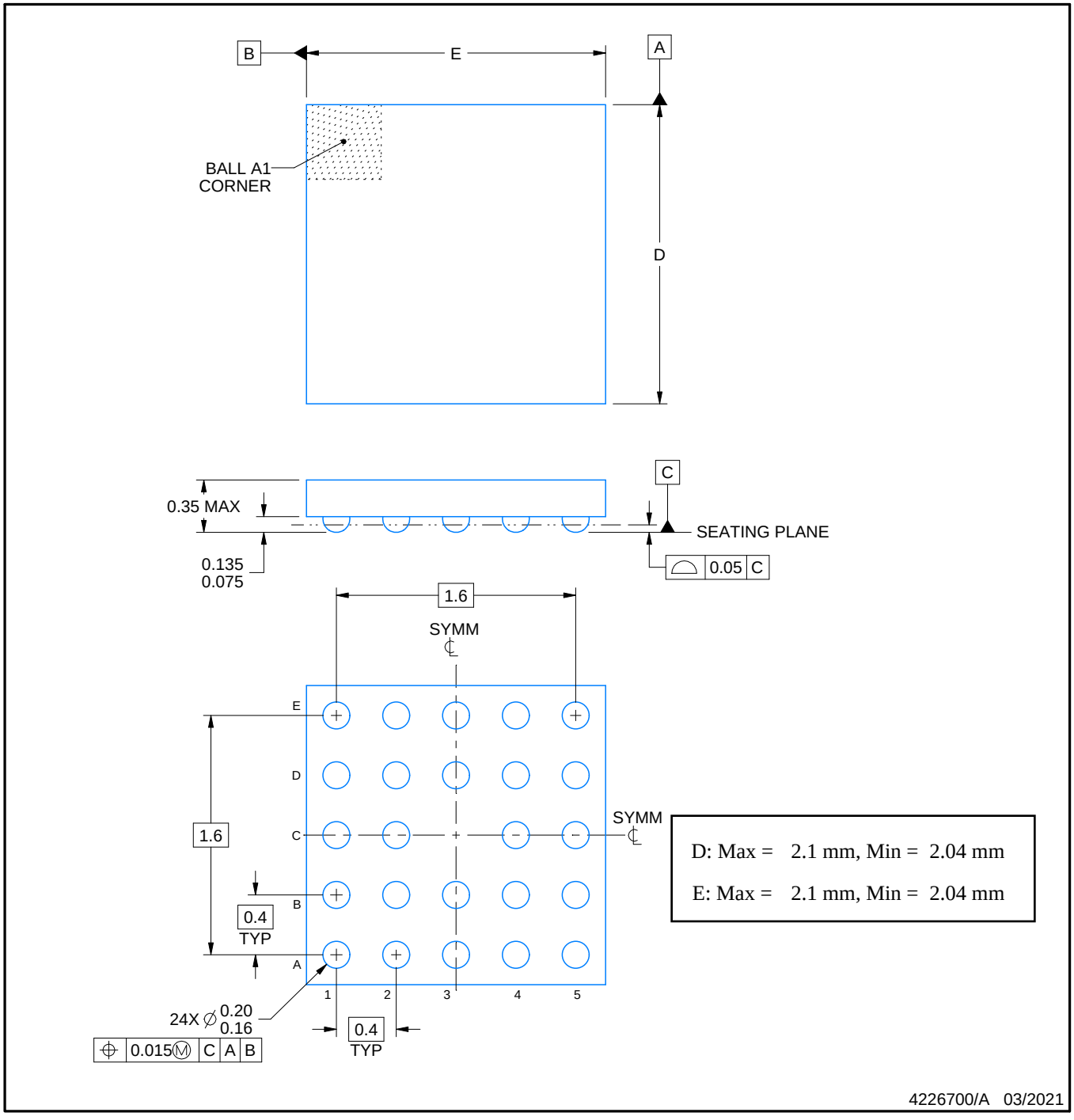
NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



NOTES:

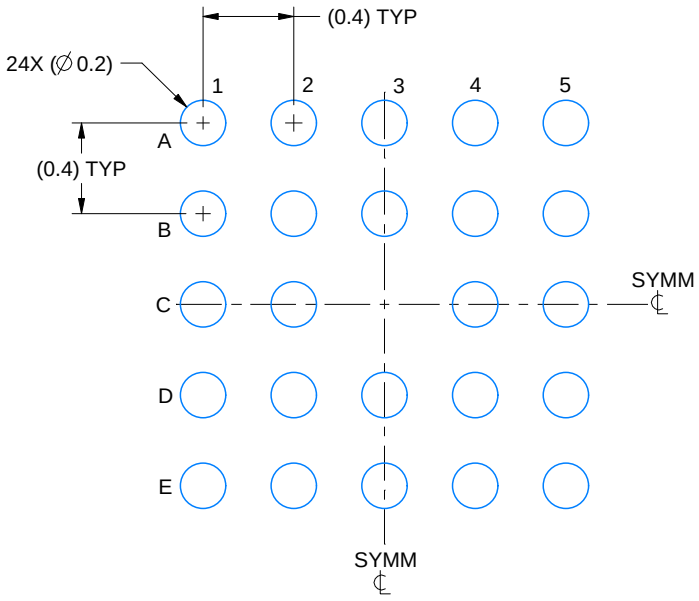
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.

EXAMPLE BOARD LAYOUT

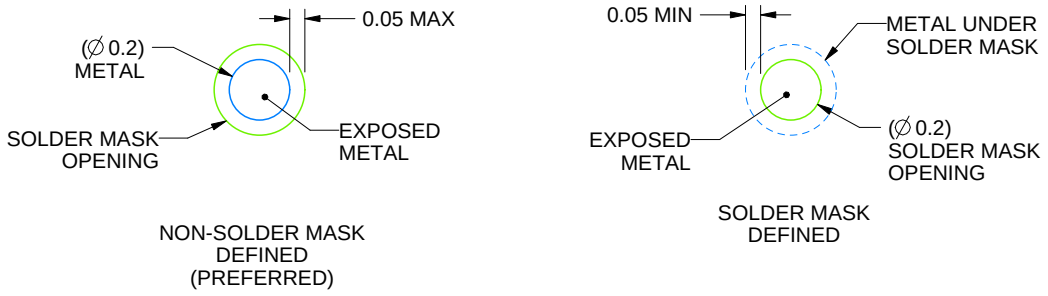
YBJ0024

DSBGA - 0.35 mm max height

DIE SIZE BALL GRID ARRAY



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 30X



SOLDER MASK DETAILS
NOT TO SCALE

4226700/A 03/2021

NOTES: (continued)

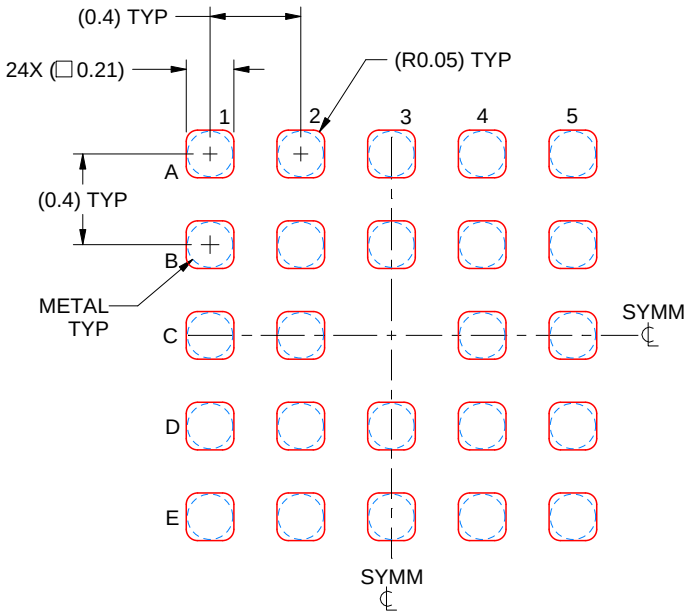
3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints.
   See Texas Instruments Literature No. SNVA009 (www.ti.com/lit/snva009).

EXAMPLE STENCIL DESIGN

YBJ0024

DSBGA - 0.35 mm max height

DIE SIZE BALL GRID ARRAY



SOLDER PASTE EXAMPLE
BASED ON 0.1 mm THICK STENCIL
SCALE: 30X

4226700/A 03/2021

NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.

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